

SLC-A Test Report

Summary Report Page – All Tests

SNIA Solid State Storage Performance Test Specification (PTS)						Rev. PTS 1.0	
						Page 1 of 31	
Device Under Test (DUT)	SLC-A	SNIA SSS PTS Summary Report		Calypso Systems, Inc.		CALYPSO Systems	
DEVICE INFORMATION		TEST HARDWARE PLATFORM		TEST SOFTWARE		REPORT DATE	
SERIAL NO.	1111-0000-FFFF	SYSTEM	Calypso RTP 2.0	SYS OS	CENT OS 5.6	Report	06DEC11
0105	BFOA	Motherboard/cpu	Intel 5520HC / W5580	SW TOOL	Calypso CTS 6.5	Test Run	01NOV – 04DEC11
USER CAPACITY	SLC 100 GB	RAM	12GB ECC DDR3	SW Rev	1.19.10	Test Sponsor	Calypso
DEVICE INTERFACE	6 Gb/s SAS	Device Interface	LSA 9212-e 6Gb/s HBA	Release	Nov. 2011	Auditor	N/A

Testing Summary: Tests Run

PTS-C	TEST	Purge	DP	OIO	WIPC		WDPC		STEADY STATE	
					PC AR	TEST AR	PC AR	TEST AR	WORKLOAD	TIME/GB
7.0	WSAT - REQUIRED	Format Unit	RND	TC 2 QD 16	100%	100%	100%	100%	RND 4KIB W	12 Hrs 2.9 TB

PTS-C	TEST	Purge	DP	OIO	WIPC		WDPC		STEADY STATE	
					PC AR	TEST AR	PC AR	TEST AR	WORKLOAD	ROUNDS
8.0	IOPS - REQUIRED	Format Unit	RND	TC 2 QD 16	100%	100%	100%	100%	IOPS LOOP	1 - 5

PTS-C	TEST	Purge	DP	OIO	WIPC		WDPC		STEADY STATE	
					PC AR	TEST AR	PC AR	TEST AR	WORKLOAD	ROUNDS
9.0	THROUGHPUT - REQUIRED	Format Unit	RND	TC 2 QD 16	100%	100%	100%	100%	SEQ 128KiB/ SEQ 1024KiB	5 - 9

PTS-C	TEST	Purge	DP	OIO	WIPC		WDPC		STEADY STATE	
					PC AR	TEST AR	PC AR	TEST AR	WORKLOAD	ROUNDS
10.0	LATENCY - REQUIRED	Format Unit	RND	TC 1 QD 1	100%	100%	100%	100%	LAT LOOP	3 - 7

Test Sponsor – Special Notes

ITEM	NOTATION	COMMENTS

SLC-A Test Report

Summary Report Page - WSAT

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Device Under Test (DUT)	SLC-A	SNIA SSS PTS Summary Report	Calypso Systems, Inc.	CALYPSO Systems			
DEVICE INFORMATION		TEST HARDWARE PLATFORM		TEST SOFTWARE	REPORT DATE		
SERIAL NO.	1111-0000-FFFF	SYSTEM	Calypso RTP 2.0	SYS OS	CENT OS 5.6	Report	06DEC11
FIRMWARE REV.	BFOA	Motherboard/cpu	Intel 5520HC / W5580	SW TOOL	Calypso CTS 6.5	Test Run	01NOV - 04DEC11
USER CAPACITY	SLC 100 GB	RAM	12GB ECC DDR3	SW Rev	1.19.10	Test Sponsor	Calypso
DEVICE INTERFACE	6 Gb/s SAS	Device Interface	LSA 9212-e 6Gb/s HBA	Release	Nov. 2011	Auditor	N/A

Test Description

Purpose	To observe the drive's performance evolution from a PURGED state to that of SETTLED state
Test Outline	Uses total outstanding IO settings that maximizes RND 4KiB Writes, first PURGE the drive, followed by immediate continuous RND 4KiB (4K-aligned) writes for lesser of 4 x User Capacity or 24 Hours
Preconditioning	FOB - No Pre Conditioning - PURGE followed by Test (note: tests may be run longer for plotting clarity)

Test Set Up

PTS-C	TEST	Purge	DP	OIO	WIPC		WDPC		STEADY STATE	
					PC AR	TEST AR	PC AR	TEST AR	WORKLOAD	TIME/GB
7.0	WSAT - REQUIRED	Format Unit	RND	TC 2 QD 16	100%	100%	100%	100%	RND 4KiB W	12 Hrs 2.9 TB

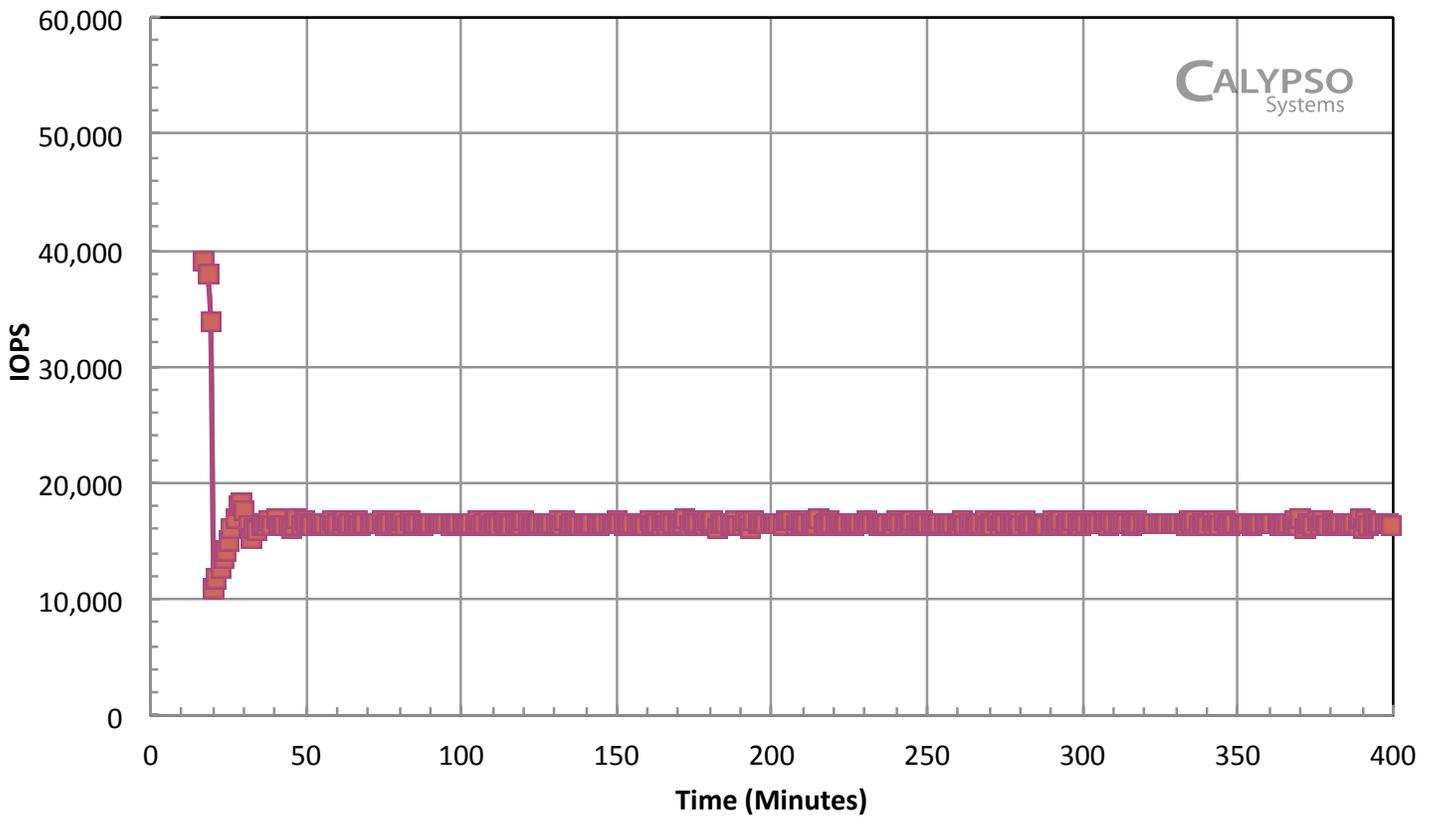
Select Performance Data

FOB IOPS	Steady State IOPS	Time	Total GB Written
39,092	16,305	12 Hours	2.9 TB

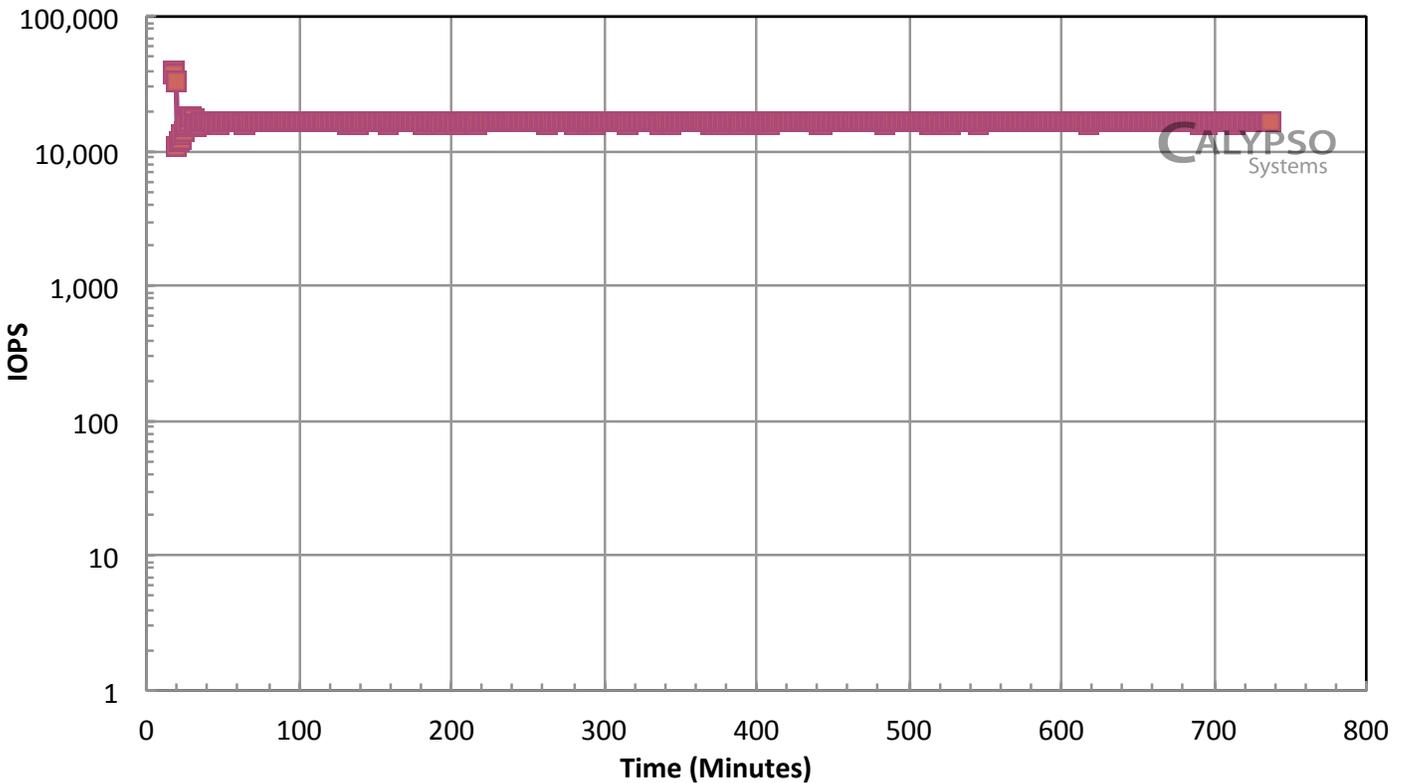
Test Sponsor – Special Notes

ITEM	NOTATION	COMMENTS

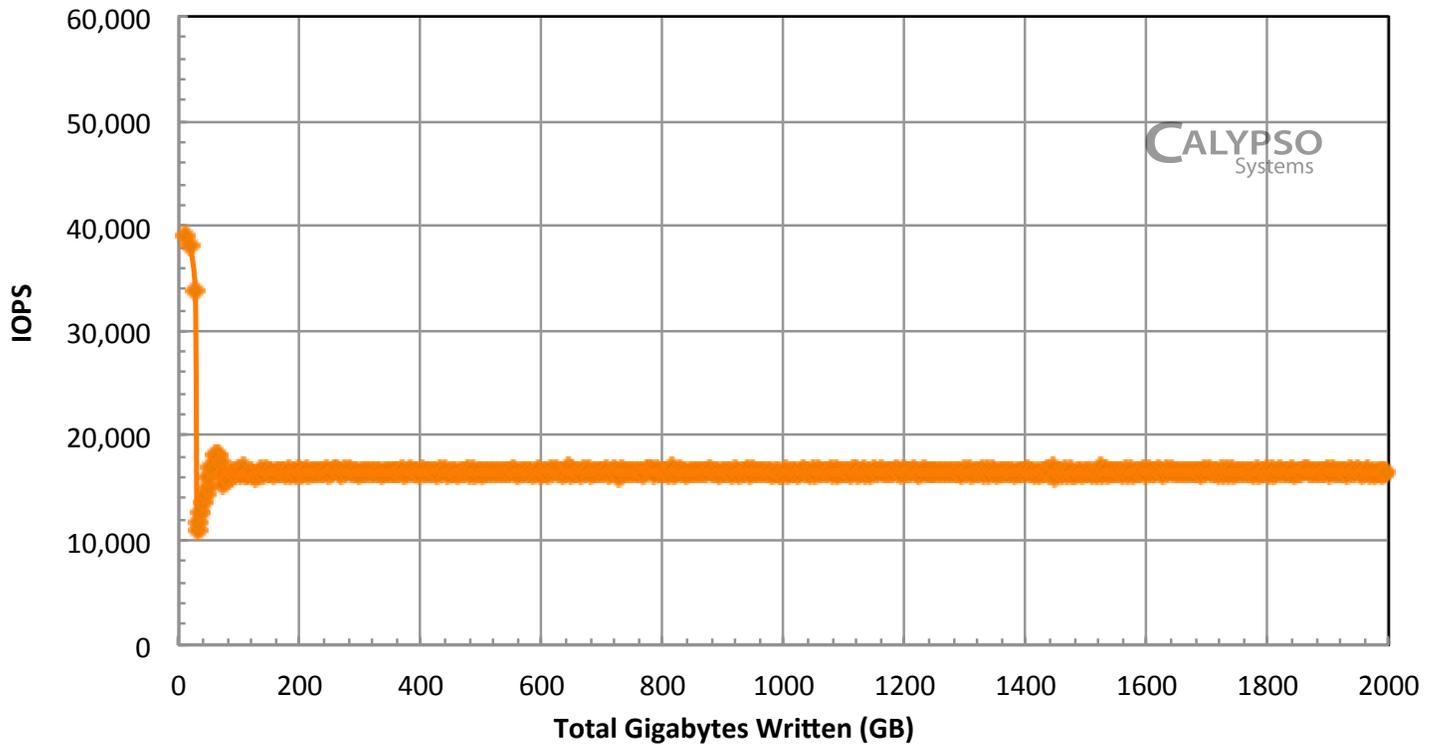
Test Run Date: 11/07/11 08:40 AM		Report Run Date: 11/14/2011 08:45 AM	
Enterprise WSAT (REQUIRED) - Report Page			
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)			Rev. PTS-E 1.0
			Page 1 of 4
Device Under Test (DUT)	VENDOR: ABC CO.	SSD MODEL NO: SLC-A 100 GB	TEST SPONSOR 
Serial No.	1111-0000-FFFF	DUT Preparation	Test Loop Parameters
Firmware Rev	BFOA	Purge	Format Unit
Capacity	100 GB	Pre-Conditioning	
NAND Type	SLC	Workload Independent	None
Device I/F	6 Gb/s SAS		
Test Platform	RTP 2.0 CTS 6.5	Workload Dep.	RND 4KiB
		REQUIRED:	Convergence
		Data Pattern	RND
		Tester's Choice:	Rounds
		OIO/Thread (QD)	16
		Thread Count (TC)	2
			PC AR
			100%
			AR AMOUNT
			100%
			AR Segments
			N/A
			OPT:
			N/A
Enterprise IOPS (Linear) vs Time (Linear)			



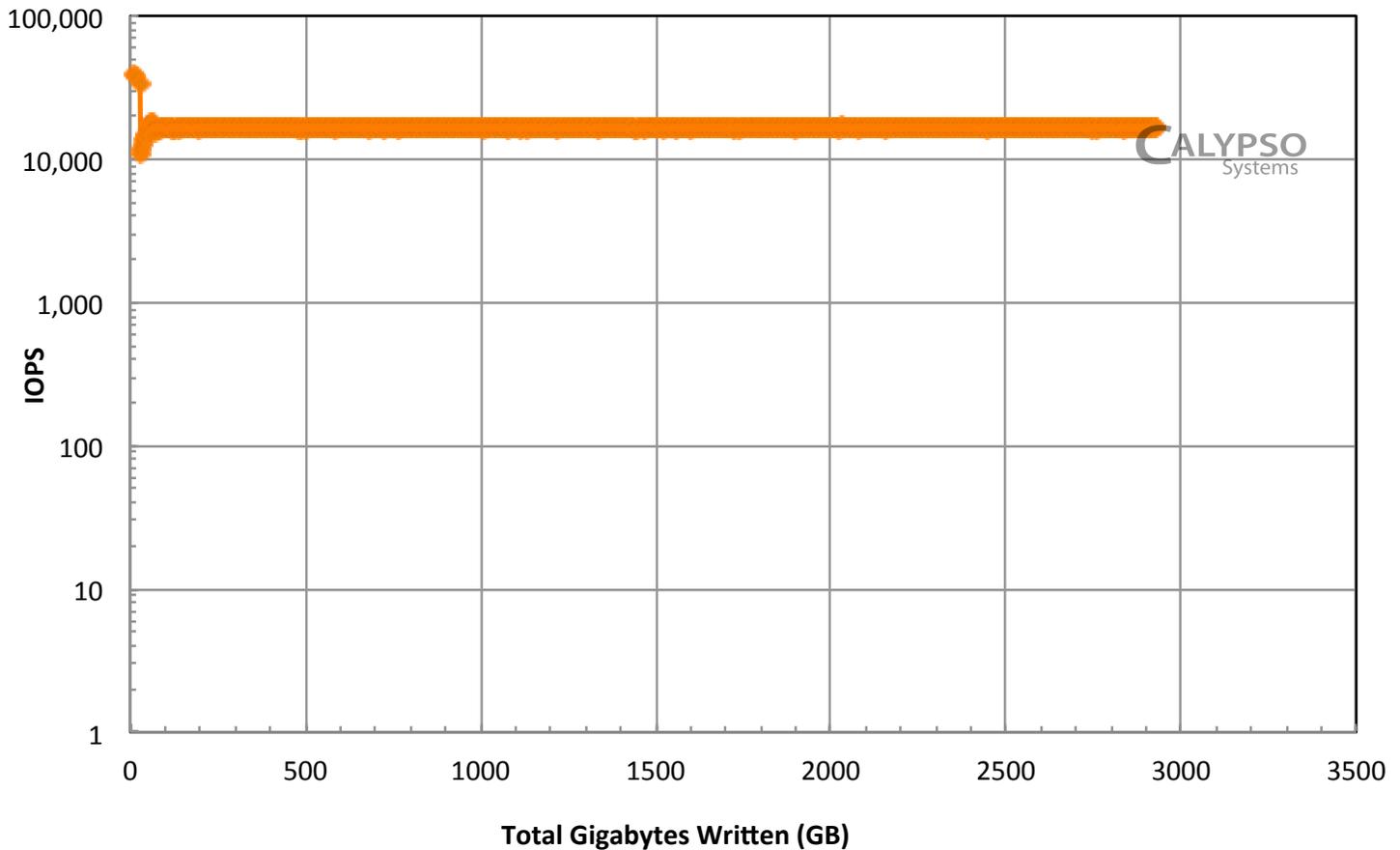
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Enterprise WSAT (REQUIRED) - Report Page			
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)			Rev. PTS-E 1.0
			Page 2 of 4
Device Under Test (DUT)	VENDOR: ABC CO.	SSD MODEL NO: SLC-A 100 GB	TEST SPONSOR 
Serial No.	1111-0000-FFFF	DUT Preparation	Test Loop Parameters
Firmware Rev	BFOA	Purge	Format Unit
Capacity	100 GB	Pre-Conditioning	
NAND Type	SLC	Workload Independent	None
Device I/F	6 Gb/s SAS		
Test Platform	RTP 2.0 CTS 6.5	Workload Dep.	RND 4KiB
		REQUIRED:	Data Pattern
		Tester's Choice:	RND
		OIO/Thread (QD)	16
		Thread Count (TC)	2
Convergence			N/A
Rounds			N/A
PC AR			100%
AR AMOUNT			100%
AR Segments			N/A
OPT:			N/A
Enterprise IOPS (LOG) vs Time (Linear)			



Test Run Date: 11/07/11 08:40 AM		Report Run Date: 11/14/2011 08:45 AM	
Enterprise WSAT (REQUIRED) - Report Page			
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)			Rev. PTS-E 1.0
			Page 3 of 4
Device Under Test (DUT)	VENDOR: ABC CO.	SSD MODEL NO: SLC-A 100 GB	TEST SPONSOR 
Serial No.	1111-0000-FFFF	DUT Preparation	Test Loop Parameters
Firmware Rev	BFOA	Purge	REQUIRED:
Capacity	100 GB	Format Unit	Data Pattern
NAND Type	SLC	Pre-Conditioning	RND
Device I/F	6 Gb/s SAS	Workload Independent	Tester's Choice:
Test Platform	RTP 2.0 CTS 6.5	None	OIO/Thread (QD)
		Workload Dep.	RND 4KiB
			Thread Count (TC)
			16
			2
			Convergence
			N/A
			Rounds
			N/A
			PC AR
			100%
			AR AMOUNT
			100%
			AR Segments
			N/A
			OPT:
			N/A
Enterprise IOPS (Linear) vs TGBW (Linear)			



Test Run Date: 11/07/11 08:40 AM		Report Run Date: 11/14/2011 08:45 AM	
Enterprise WSAT (REQUIRED) - Report Page			
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)			Rev. PTS-E 1.0
			Page 4 of 4
Device Under Test (DUT)	VENDOR: ABC CO.	SSD MODEL NO: SLC-A 100 GB	TEST SPONSOR 
Serial No.	1111-0000-FFFF	DUT Preparation	Test Loop Parameters
Firmware Rev	BFOA	Purge	Format Unit
Capacity	100 GB	Pre-Conditioning	
NAND Type	SLC	Workload Independent	None
Device I/F	6 Gb/s SAS		
Test Platform	RTP 2.0 CTS 6.5	Workload Dep.	RND 4KiB
		REQUIRED:	Convergence
		Data Pattern	RND
		Tester's Choice:	Rounds
		OIO/Thread (QD)	16
		Thread Count (TC)	2
			PC AR
			100%
			AR AMOUNT
			100%
			AR Segments
			N/A
			OPT:
			N/A
Enterprise IOPS (LOG) vs TGBW (Linear)			



SLC-A Test Report

Summary Report Page - IOPS

SNIA Solid State Storage Performance Test Specification (PTS)	Rev.	PTS 1.0
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Device Under Test (DUT)	SLC-A	SNIA SSS PTS Summary Report	Calypso Systems, Inc.			
DEVICE INFORMATION		TEST HARDWARE PLATFORM	TEST SOFTWARE		REPORT DATE	
SERIAL NO.	1111-0000-FFFF	SYSTEM	Calypso RTP 2.0		Report	06DEC11
FIRMWARE REV.	BFOA	Motherboard/cpu	Intel 5520HC / W5580		Test Run	01NOV - 04DEC11
USER CAPACITY	SLC 100 GB	RAM	12GB ECC DDR3		Test Sponsor	Calypso
DEVICE INTERFACE	6 Gb/s SAS	Device Interface	LSA 9212-e 6Gb/s HBA		Auditor	N/A

Test Description

Purpose	To measure RND IOPS matrix using different BS and R/W Mixes
Test Outline	PURGE, then apply preconditioning until Steady State is achieved according to the SNIA PTS
Preconditioning	PURGE followed by SNIA PTS prescribed WIPC & WDPC

Test Set Up

PTS-C	TEST	Purge	DP	OIO	WIPC		WDPC		STEADY STATE	
8.0	IOPS - REQUIRED	Format Unit	RND	TC 2 QD 16	PC AR	TEST AR	PC AR	TEST AR	WORKLOAD	ROUNDS
					100%	100%	100%	100%	IOPS LOOP	1 - 5

Select Performance Data

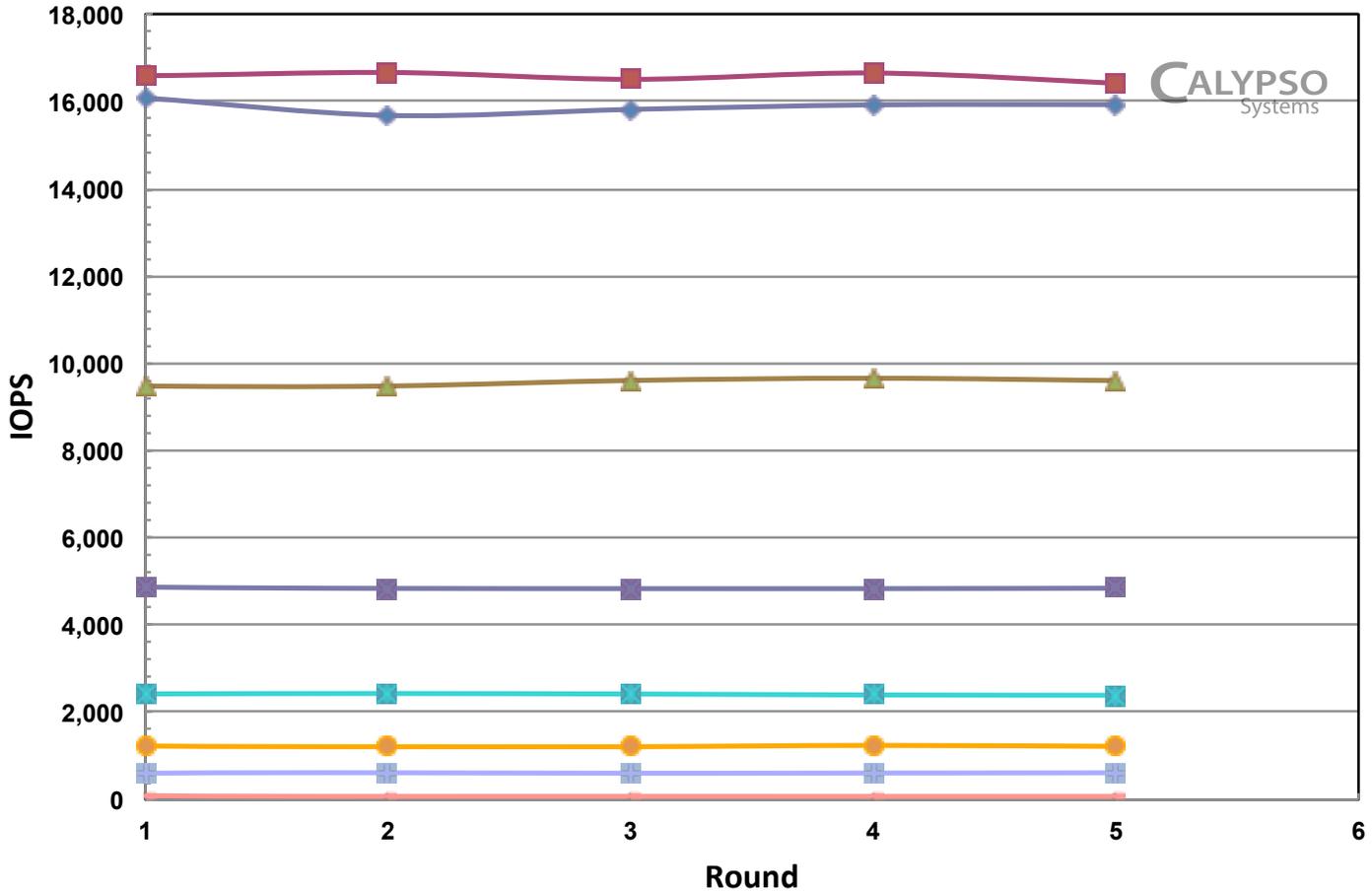
RND 4KiB W	RND 4KiB R	RND 8KiB W	RND 8KiB R
16,887	93,707	9,560	50,301

Test Sponsor – Special Notes

ITEM	NOTATION	COMMENTS

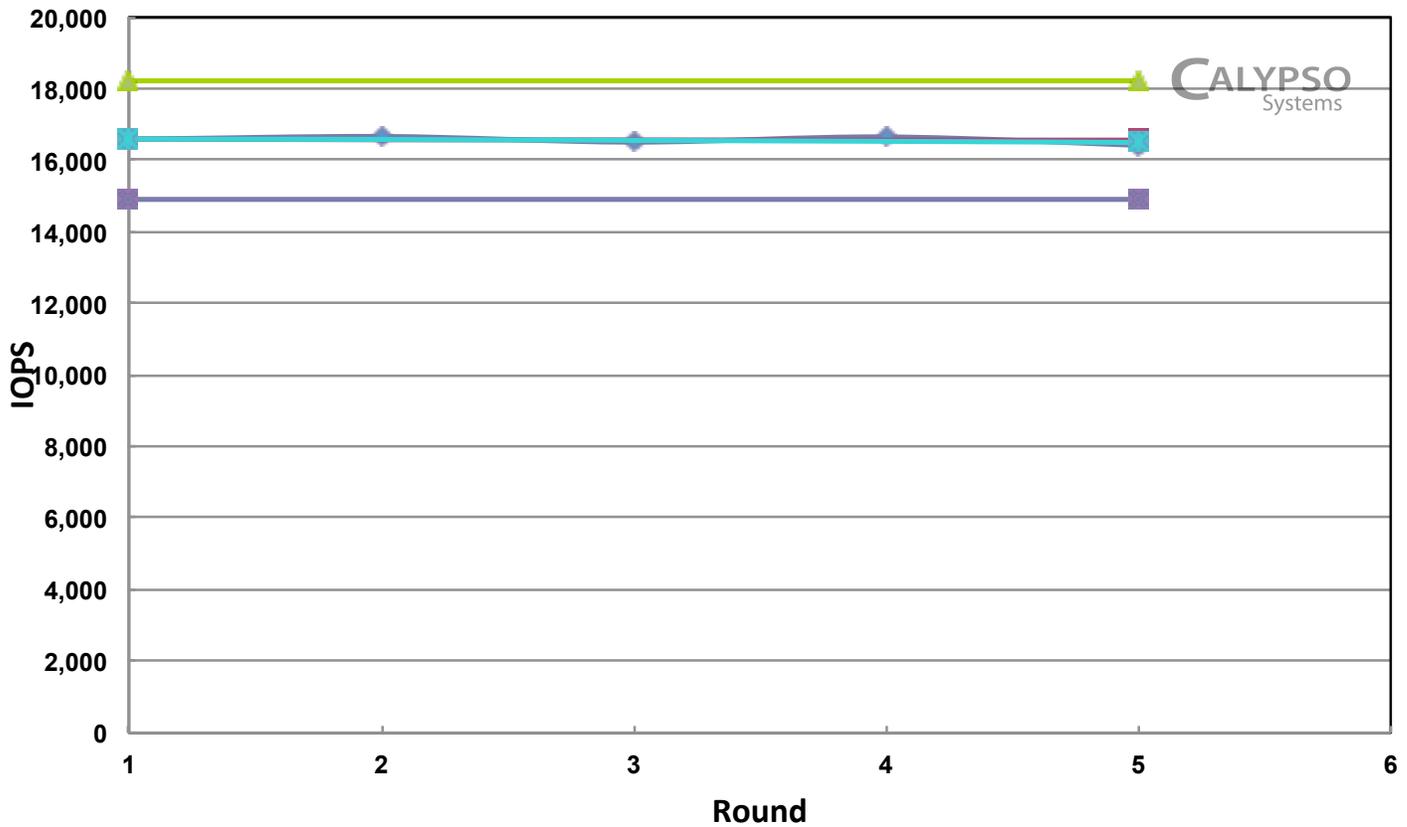
Test Run Date: 11/02/2011 02:56 PM		Report Run Date: 11/14/2011 08:43 AM	
Enterprise IOPS (REQUIRED) - Report Page			
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)			Rev. PTS-E 1.0
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Device Under Test (DUT)	VENDOR: ABC CO.	SSD MODEL NO: SLC-A 100 GB	TEST SPONSOR CALYPSO Systems
Serial No.	1111-0000-FFFF	DUT Preparation	Test Loop Parameters
Firmware Rev	BFOA	Purge	REQUIRED:
Capacity	100 GB	Format Unit	Data Pattern
NAND Type	SLC	Pre-Conditioning	RND
Device I/F	6 Gb/s SAS	Workload Independent	Tester's Choice:
Test Platform	RTP 2.0 CTS 6.5	2X SEQ/128KiB	OIO/Thread (QD)
		Workload Dep.	16
		Full IOPS Loop	Thread Count (TC)
			2
			Steady State
			Convergence
			YES
			Rounds
			1-5
			PC AR
			100%
			AR AMOUNT
			100%
			AR Segments
			N/A
Enterprise Steady State Convergence Plot - All Block Sizes			

BS=0.5 KiB BS=4 KiB BS=8 KiB BS=16 KiB BS=32 KiB BS=64 KiB BS=128 KiB BS=1024 KiB



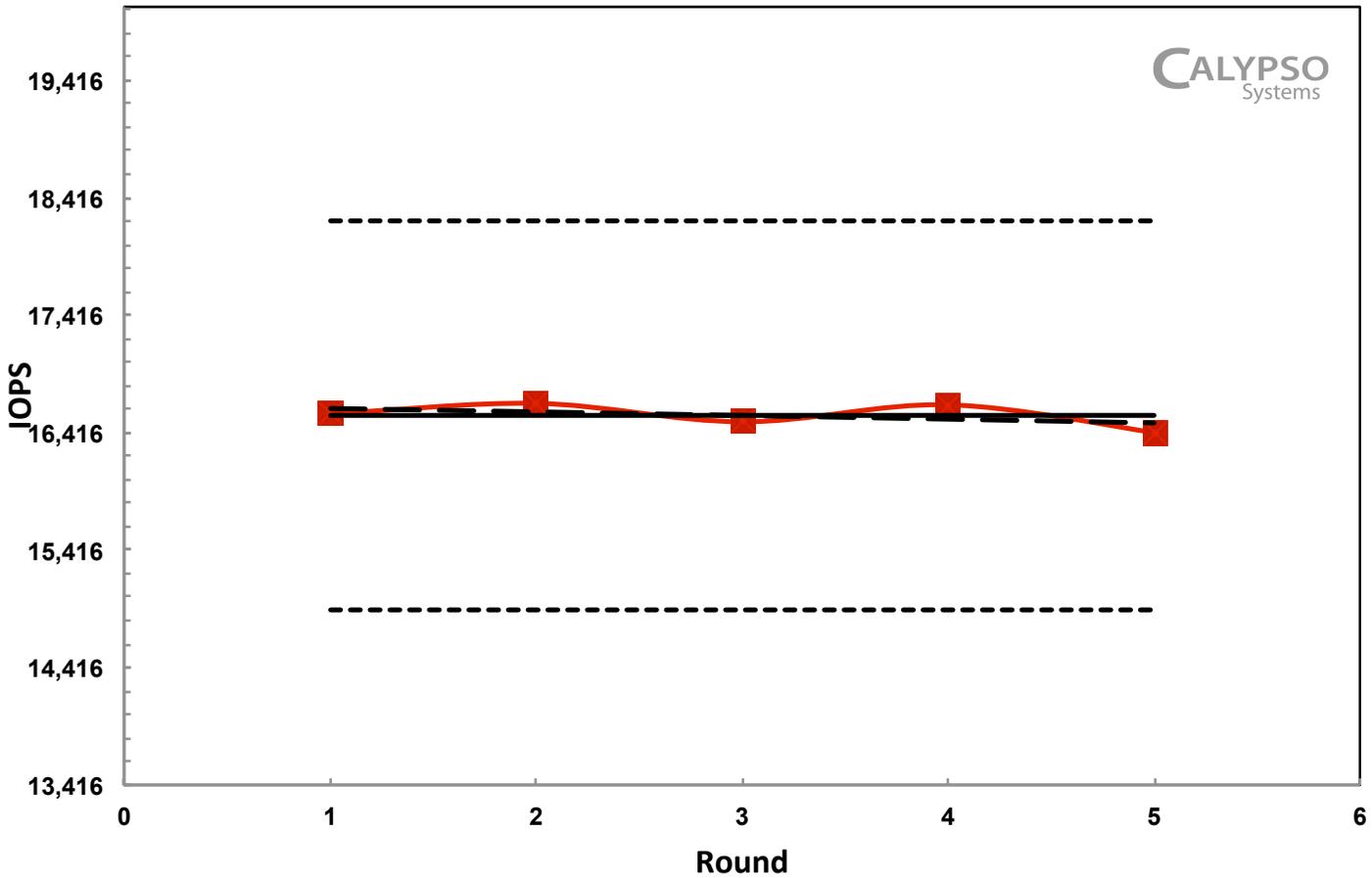
Test Run Date: 11/02/2011 02:56 PM		Report Run Date: 11/14/2011 08:43 AM	
Enterprise IOPS (REQUIRED) - Report Page			
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)			Rev. E-1.0
			Page 2 of 6
Device Under Test (DUT)	VENDOR: ABC CO.	SSD MODEL NO: SLC-A 100 GB	TEST SPONSOR CALYPSO Systems
Serial No.	1111-0000-FFFF	DUT Preparation	
Firmware Rev	BFOA	Purge	Format Unit
Capacity	100 GB	Pre-Conditioning	
NAND Type	SLC	Workload Independent	2X SEQ/128KiB
Device I/F	6 Gb/s SAS		
Test Platform	RTP 2.0 CTS 6.5	Workload Dep.	Full IOPS Loop
		REQUIRED:	Test Loop Parameters
		Data Pattern	RND
		Tester's Choice:	
		OIO/Thread (QD)	16
		Thread Count (TC)	2
			Steady State
			Convergence
			YES
			Rounds
			1-5
			PC AR
			100%
			AR AMOUNT
			100%
			AR Segments
			N/A
Enterprise Steady State Measurement Window			

◆ IOPS
■ Average
▲ 110%*Average
■ 90%*Average
■ Slope



Test Run Date: 11/02/2011 02:56 PM		Report Run Date: 11/14/2011 08:43 AM	
Enterprise IOPS (REQUIRED) - Report Page			
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)			Rev. PTS-E 1.0
			Page 3 of 6
Device Under Test (DUT)	VENDOR: ABC CO.	SSD MODEL NO: SLC-A 100 GB	TEST SPONSOR CALYPSO Systems
Serial No.	1111-0000-FFFF	DUT Preparation	Test Loop Parameters
Firmware Rev	BFOA	Purge	Format Unit
Capacity	100 GB	Pre-Conditioning	
NAND Type	SLC	Workload Independent	2X SEQ/128KiB
Device I/F	6 Gb/s SAS		
Test Platform	RTP 2.0 CTS 6.5	Workload Dep.	Full IOPS Loop
		REQUIRED:	Data Pattern
		Tester's Choice:	RND
		OIO/Thread (QD)	16
		Thread Count (TC)	2
		Convergence	YES
		Rounds	1-5
		PC AR	100%
		AR AMOUNT	100%
		AR Segments	N/A
Enterprise Steady State Measurement Window – RND/4KiB			

■ IOPS
 Average
 110%*Average
 90%*Average
 Slope



Steady State Determination Data

Average IOPS:	16563.0		
Allowed Maximum Data Excursion:	3312.6	Measured Maximum Data Excursion:	248.3
Allowed Maximum Slope Excursion:	1656.3	Measured Maximum Slope Excursion:	128.6
Least Squares Linear Fit Formula:	-32.143 * R + 16659.425		

Test Run Date: 11/02/2011 02:56 PM		Report Run Date: 11/14/2011 08:43 AM					
Enterprise IOPS (REQUIRED) - Report Page							
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)			Rev. PTS-E 1.0				
			Page 4 of 6				
Device Under Test (DUT)	VENDOR: ABC CO.	SSD MODEL NO: SLC-A 100 GB	TEST SPONSOR 				
Serial No.	1111-0000-FFFF	DUT Preparation	Test Loop Parameters				
Firmware Rev	BFOA	Purge	REQUIRED:				
Capacity	100 GB	Format Unit	Data Pattern				
NAND Type	SLC	Pre-Conditioning	RND				
Device I/F	6 Gb/s SAS	Workload Independent	Tester's Choice:				
Test Platform	RTP 2.0 CTS 6.5	Workload Dep.	OIO/Thread (QD)				
		2X SEQ/128KiB	16				
		Full IOPS Loop	Thread Count (TC)				
			2				
Enterprise IOPS - ALL RW Mix & BS - Tabular Data							
Block Size (KiB)	Read / Write Mix %						
	0/100	5/95	35/65	50/50	65/35	95/5	100/0
0.5	15,887.4	16,634.7	20,678.6	24,402.8	29,386.2	72,428.4	95,924.3
4	16,563.0	17,032.2	20,234.2	23,705.2	28,018.6	63,447.7	93,707.0
8	9,559.8	9,998.4	12,547.1	14,636.6	17,199.1	37,872.9	50,301.2
16	4,842.2	5,032.3	6,802.5	8,132.1	9,655.8	22,462.2	31,072.8
32	2,413.3	2,535.4	3,478.4	4,241.3	5,061.7	12,174.7	15,994.2
64	1,219.2	1,275.7	1,728.4	2,126.1	2,726.3	6,284.6	8,094.9
128	612.7	632.5	859.1	1,061.4	1,709.4	3,205.7	4,060.8
1024	74.8	78.0	103.6	126.7	202.7	398.8	514.6

Test Run Date: 11/02/2011 02:56 PM

Report Run Date: 11/14/2011 08:43 AM

Enterprise IOPS (REQUIRED) - Report Page

SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)

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Device Under Test (DUT)

VENDOR:
ABC CO.

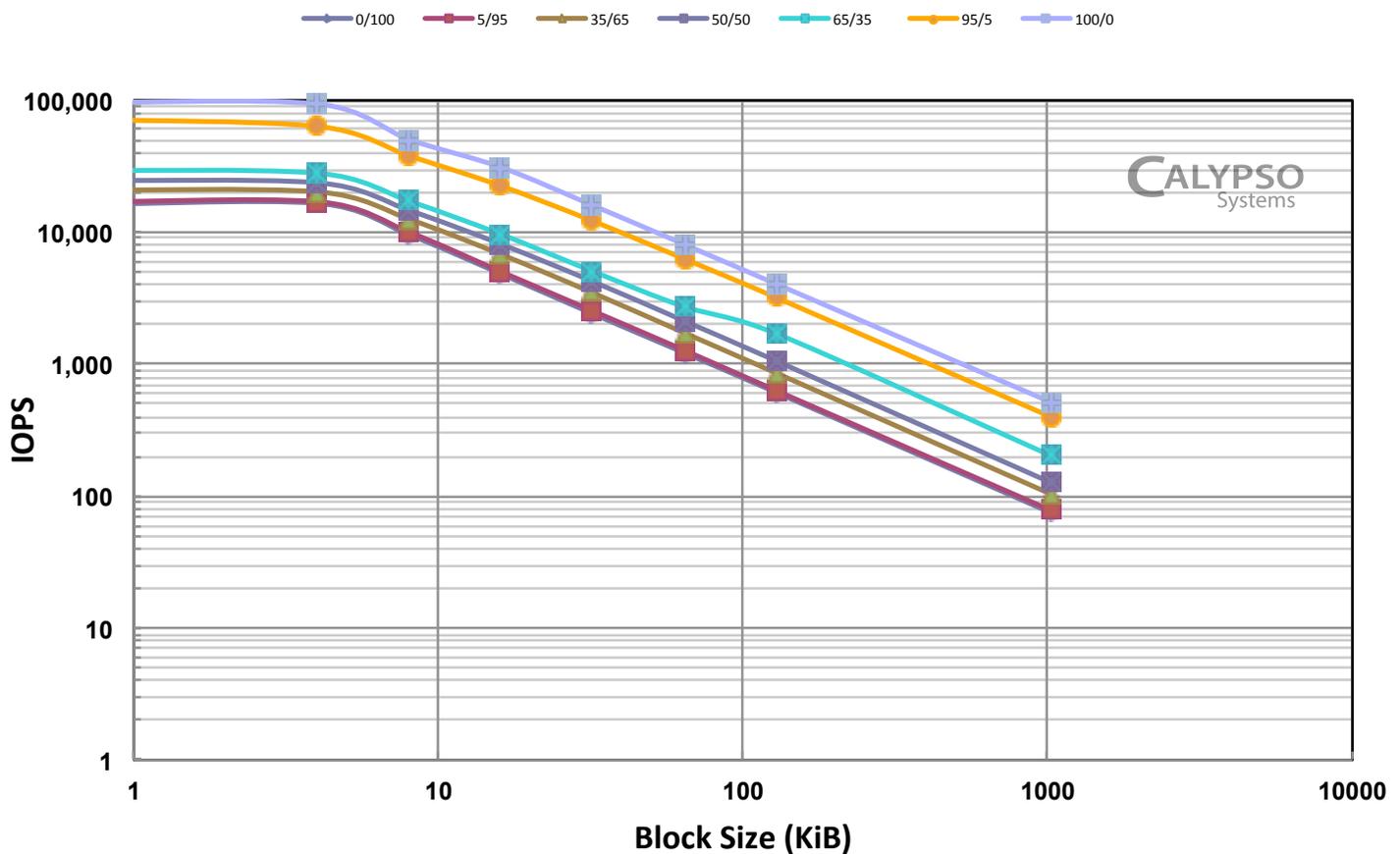
SSD MODEL NO:
SLC-A 100 GB

TEST SPONSOR



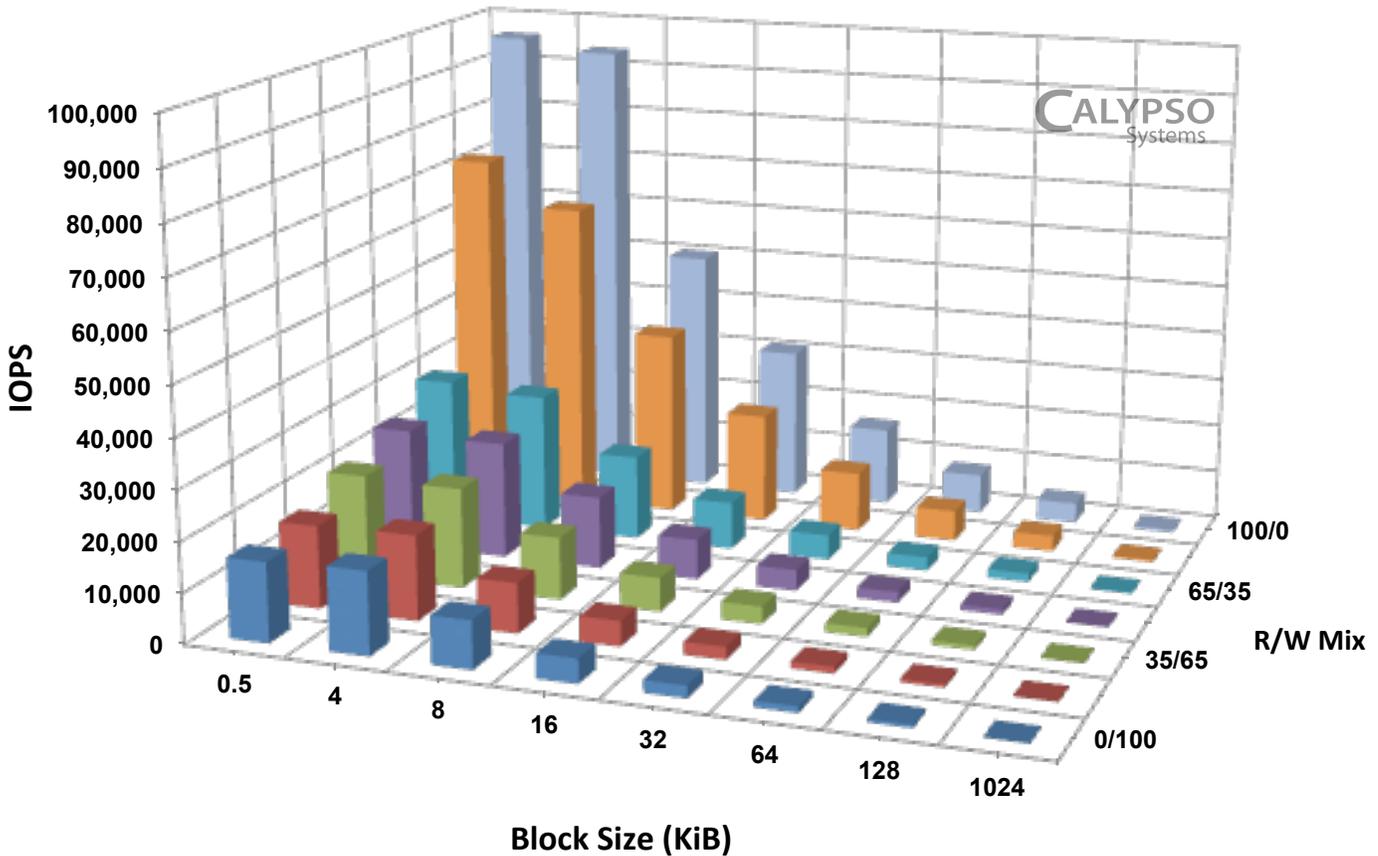
Serial No.	1111-0000-FFFF	DUT Preparation		Test Loop Parameters		Steady State	
Firmware Rev	BFOA	Purge	Format Unit	REQUIRED:	RND	Convergence	YES
Capacity	100 GB	Pre-Conditioning				Data Pattern	Rounds
NAND Type	SLC	Workload Independent	2X SEQ/128KiB	Tester's Choice:	16	PC AR	100%
Device I/F	6 Gb/s SAS		Full IOPS Loop			OIO/Thread (QD)	AR AMOUNT
Test Platform	RTP 2.0 CTS 6.5	Workload Dep.			Thread Count (TC)	2	AR Segments

Enterprise IOPS - ALL RW Mix & BS - 2D Plot



Test Run Date: 11/02/2011 02:56 PM		Report Run Date: 11/14/2011 08:43 AM	
Enterprise IOPS (REQUIRED) - Report Page			
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)			Rev. PTS-E 1.0
			Page 6 of 6
Device Under Test (DUT)	VENDOR: ABC CO.	SSD MODEL NO: SLC-A 100 GB	TEST SPONSOR CALYPSO Systems
Serial No.	1111-0000-FFFF	DUT Preparation	Test Loop Parameters
Firmware Rev	BFOA	Purge	Format Unit
Capacity	100 GB	REQUIRED:	
NAND Type	SLC	Data Pattern	
Device I/F	6 Gb/s SAS	RND	
Test Platform	RTP 2.0 CTS 6.5	Tester's Choice:	
		OIO/Thread (QD)	16
		Thread Count (TC)	2
		Steady State	
		Convergence	YES
		Rounds	1-5
		PC AR	100%
		AR AMOUNT	100%
		AR Segments	N/A
Enterprise IOPS - ALL RW Mix & BS - 3D Columns			

■ 0/100 ■ 5/95 ■ 35/65 ■ 50/50 ■ 65/35 ■ 95/5 ■ 100/0



SLC-A Test Report

Summary Report Page - THROUGHPUT

SNIA Solid State Storage Performance Test Specification (PTS)

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Device Under Test (DUT)

SLC-A

**SNIA SSS PTS
Summary Report**

**Calypso
Systems, Inc.**

**CALYPSO
Systems**

DEVICE INFORMATION		TEST HARDWARE PLATFORM		TEST SOFTWARE		REPORT DATE	
SERIAL NO.	1111-0000-FFFF	SYSTEM	Calypso RTP 2.0	SYS OS	CENT OS 5.6	Report	06DEC11
FIRMWARE REV.	BFOA	Motherboard/cpu	Intel 5520HC / W5580	SW TOOL	Calypso CTS 6.5	Test Run	01NOV - 04DEC11
USER CAPACITY	SLC 100 GB	RAM	12GB ECC DDR3	SW Rev	1.19.10	Test Sponsor	Calypso
DEVICE INTERFACE	6 Gb/s SAS	Device Interface	LSA 9212-e 6Gb/s HBA	Release	Nov. 2011	Auditor	N/A

Test Description

Purpose	To measure Large Block SEQ TP using different BS and R/W Mixes
Test Outline	PURGE, then apply preconditioning until Steady State is achieved according to the SNIA PTS
Preconditioning	PURGE followed by SNIA PTS prescribed WIPC & WDPC

Test Set Up

PTS-C	TEST	Purge	DP	OIO	WIPC		WDPC		STEADY STATE	
9.0	THROUGHPUT - REQUIRED	Format Unit	RND	TC 2 QD 16	PC AR	TEST AR	PC AR	TEST AR	WORKLOAD	ROUNDS
					100%	100%	100%	100%	SEQ 128KiB/ SEQ 1024KiB	5 - 9

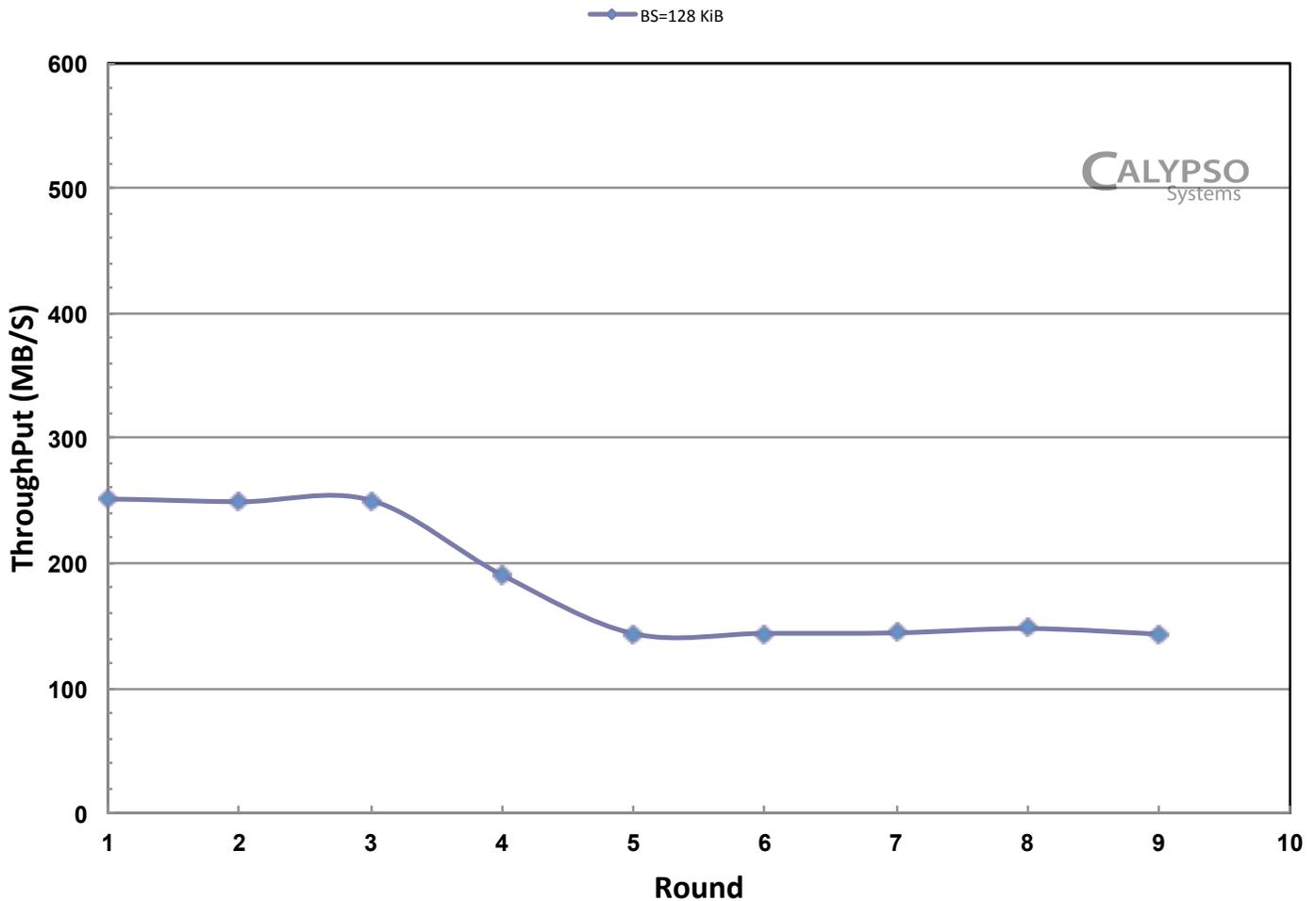
Select Performance Data

SEQ 128KiB R	SEQ 128KiB W	SEQ 1024KiB R	SEQ 1024KiB W
409 MB/S	145 MB/S	514 MB/S	157 MB/S

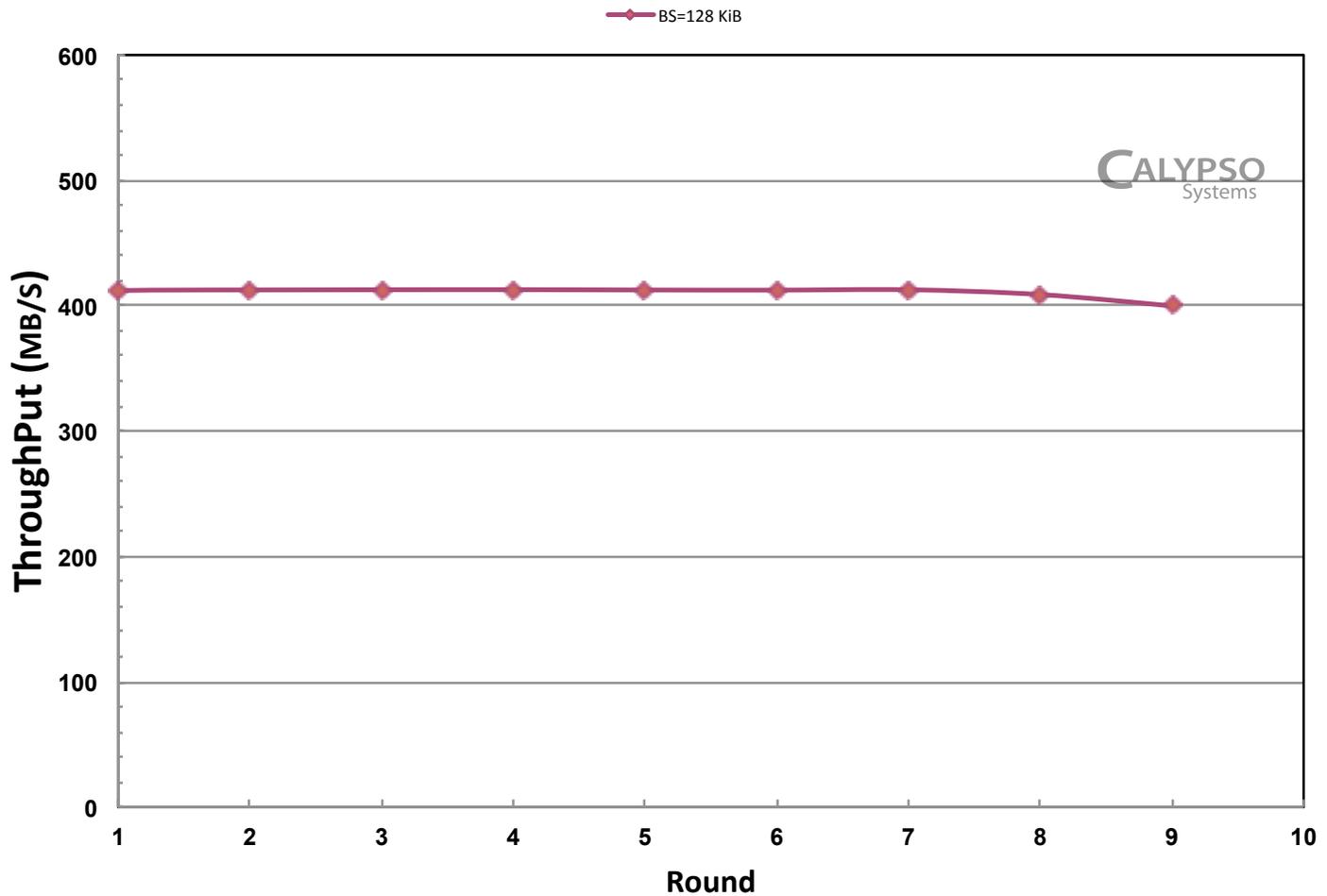
Test Sponsor – Special Notes

ITEM	NOTATION	COMMENTS

Test Run Date: 12/03/2011 04:32 PM		Report Run Date: 12/04/2011 10:04 AM	
Enterprise Throughput Test (REQUIRED) - Report Page			
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)			Rev. PTS-E 1.0
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Device Under Test (DUT)	VENDOR: ABC CO.	SSD MODEL NO: SLC-A 100 GB	TEST SPONSOR CALYPSO Systems
Serial No.	1111-0000-FFFF	DUT Preparation	Test Loop Parameters
Firmware Rev	BFOA	Purge	Format Unit
Capacity	100 GB	Pre-Conditioning	
NAND Type	SLC	Workload Independent	2X SEQ/128KiB
Device I/F	6 Gb/s SAS		
Test Platform	RTP 2.0 CTS 6.5	Workload Dep.	SEQ 128KiB
		REQUIRED:	Data Pattern
		Tester's Choice:	RND
		OIO/Thread (QD)	16
		Thread Count (TC)	2
		Convergence	YES
		Rounds	4-8
		PC AR	100%
		AR AMOUNT	100%
		AR Segments	N/A
Enterprise 128KiB Throughput Test - SS Convergence - Write			

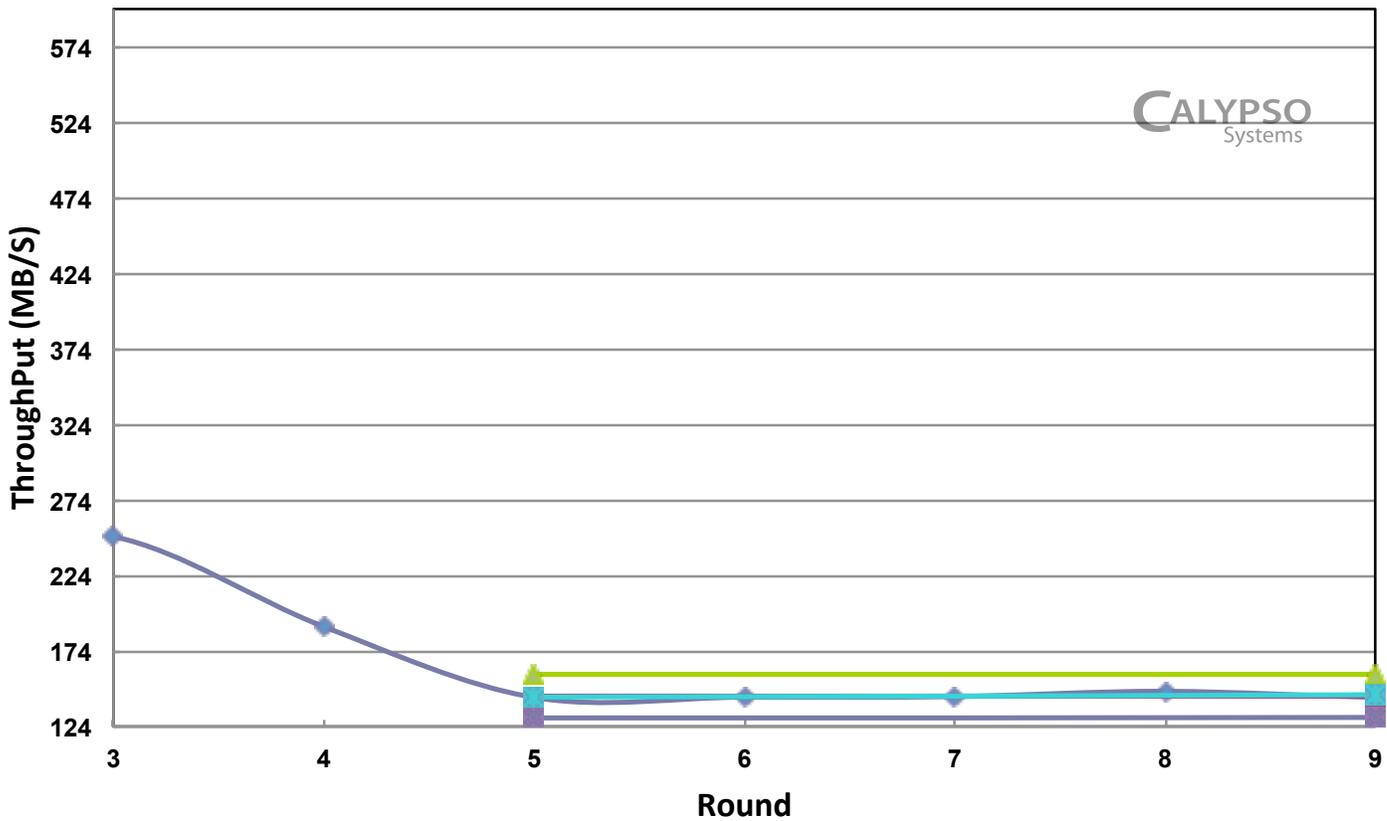


Test Run Date: 12/03/2011 04:32 PM		Report Run Date: 12/04/2011 10:04 AM	
Enterprise Throughput Test (REQUIRED) - Report Page			
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)			Rev. PTS-E 1.0
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Device Under Test (DUT)	VENDOR: ABC CO.	SSD MODEL NO: SLC-A 100 GB	TEST SPONSOR CALYPSO Systems
Serial No.	1111-0000-FFFF	DUT Preparation	Test Loop Parameters
Firmware Rev	BFOA	Purge	Format Unit
Capacity	100 GB	Pre-Conditioning	
NAND Type	SLC	Workload Independent	2X SEQ/128KiB
Device I/F	6 Gb/s SAS		
Test Platform	RTP 2.0 CTS 6.5	Workload Dep.	SEQ 128KiB
		REQUIRED:	Steady State
		Data Pattern	RND
		Tester's Choice:	
		OIO/Thread (QD)	16
		Thread Count (TC)	2
		Convergence	YES
		Rounds	4-8
		PC AR	100%
		AR AMOUNT	100%
		AR Segments	N/A
Enterprise 128KiB Throughput Test - SS Convergence - Read			



Test Run Date: 12/03/2011 04:32 PM		Report Run Date: 12/04/2011 10:04 AM	
Enterprise Throughput Test (REQUIRED) - Report Page			
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)			Rev. PTS-E 1.0
			Page 3 of 5
Device Under Test (DUT)	VENDOR: ABC CO.	SSD MODEL NO: SLC-A 100 GB	TEST SPONSOR CALYPSO Systems
Serial No.	1111-0000-FFFF	DUT Preparation	Test Loop Parameters
Firmware Rev	BFOA	Purge	Format Unit
Capacity	100 GB	REQUIRED:	
NAND Type	SLC	Data Pattern	
Device I/F	6 Gb/s SAS	RND	
Test Platform	RTP 2.0 CTS 6.5	Tester's Choice:	
		OIO/Thread (QD)	16
		Thread Count (TC)	2
		Workload Independent	2X SEQ/128KiB
		Workload Dep.	SEQ 128KiB
		Convergence	YES
		Rounds	4-8
		PC AR	100%
		AR AMOUNT	100%
		AR Segments	N/A
Enterprise Steady State Measurement Window – SEQ/128 KiB			

◆ IOPS
■ Average
▲ 110%*Average
■ 90%*Average
■ Slope



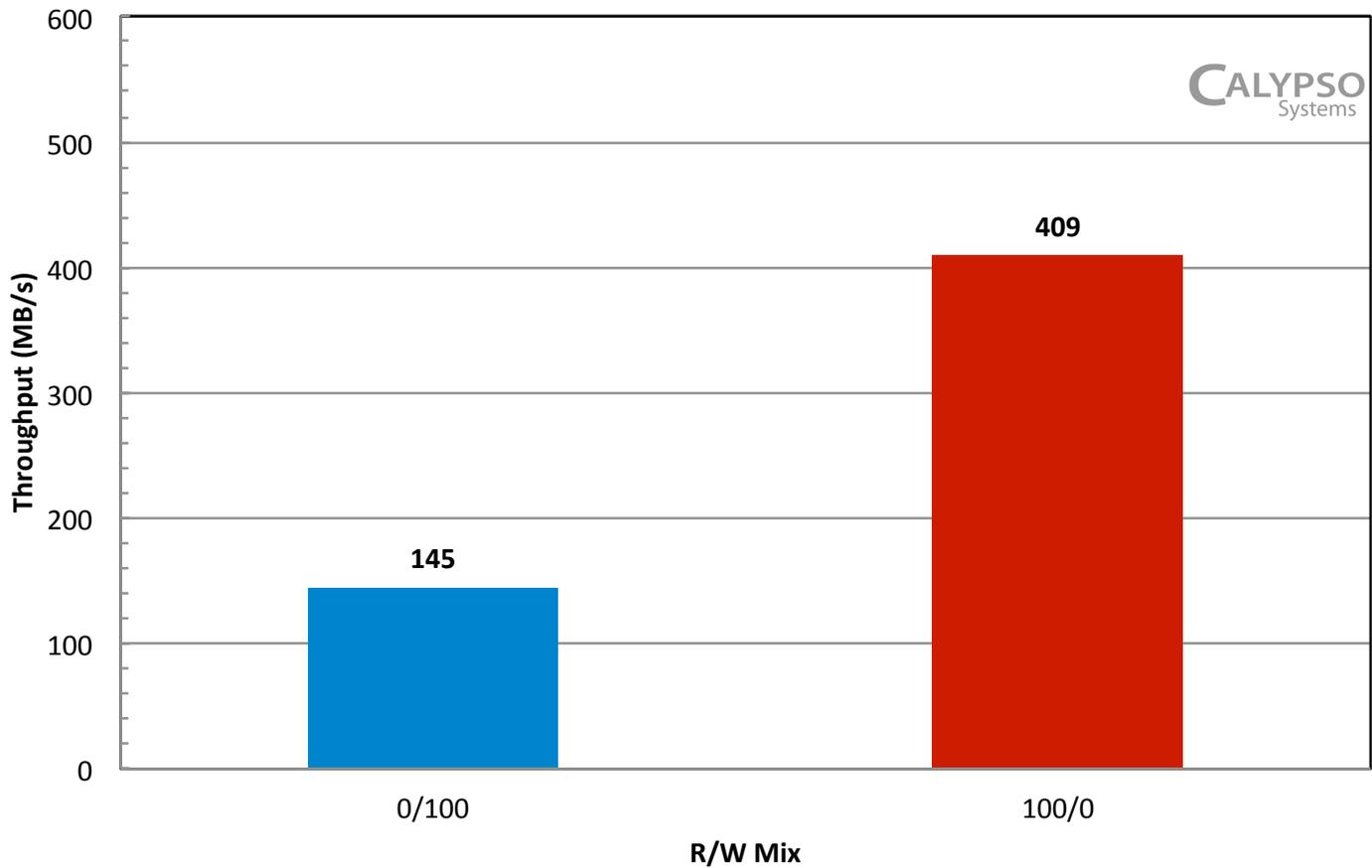
Steady State Determination Data

Average ThroughPut:	144.5		
Allowed Maximum Data Excursion:	28.9	Measured Maximum Data Excursion:	4.5
Allowed Maximum Slope Excursion:	14.4	Measured Maximum Slope Excursion:	1.2
Least Squares Linear Fit Formula:	0.2931 * R + 142.43		

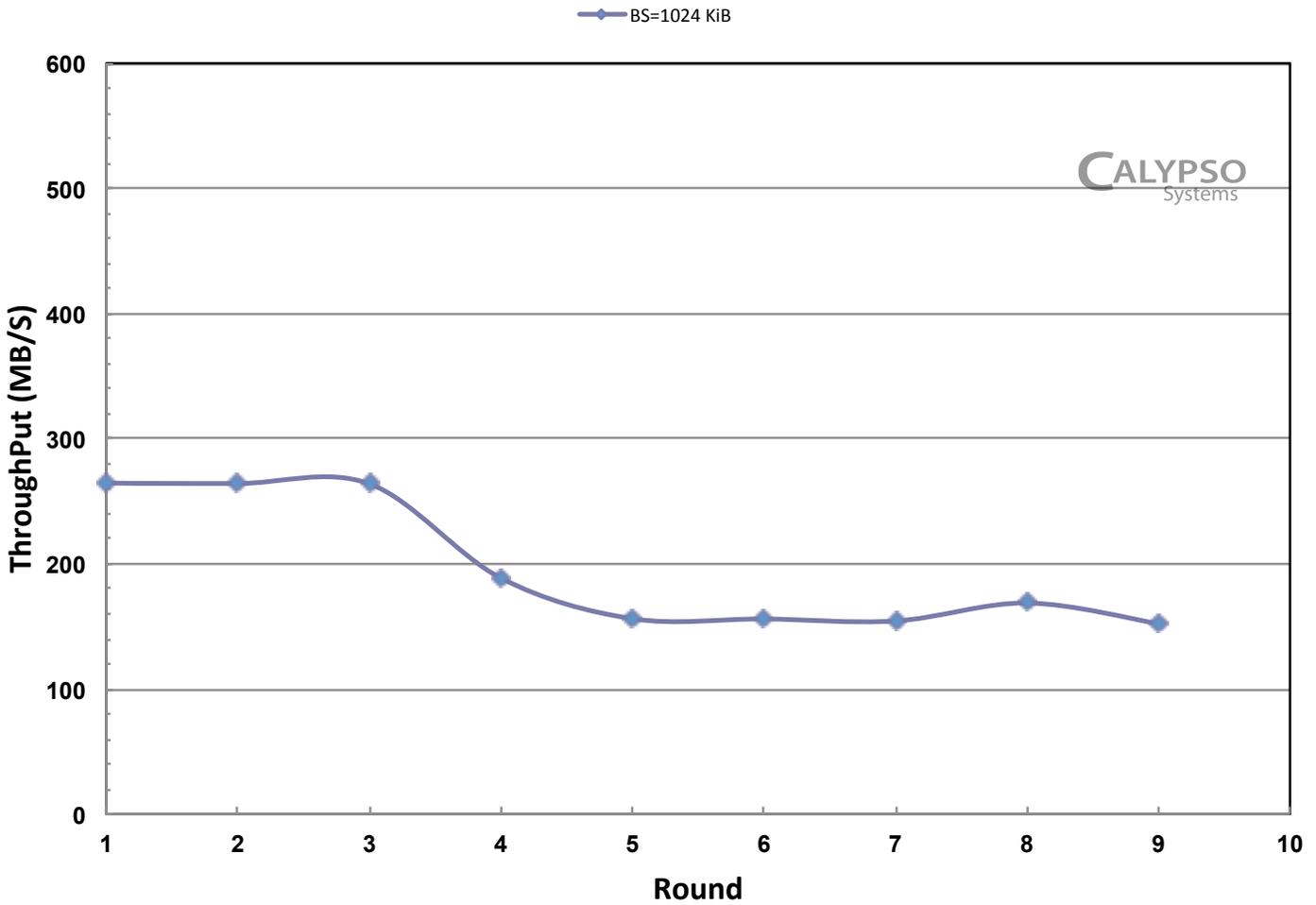
Test Run Date: 12/03/2011 04:32 PM		Report Run Date: 12/04/2011 10:04 AM	
Enterprise Throughput Test (REQUIRED) - Report Page			
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)			Rev. PTS-E 1.0
			Page 4 of 5
Device Under Test (DUT)	VENDOR: ABC CO.	SSD MODEL NO: SLC-A 100 GB	TEST SPONSOR 
Serial No.	1111-0000-FFFF	DUT Preparation	Test Loop Parameters
Firmware Rev	BFOA	Purge	Format Unit
Capacity	100 GB	Pre-Conditioning	
NAND Type	SLC	Workload Independent	2X SEQ/128KiB
Device I/F	6 Gb/s SAS		
Test Platform	RTP 2.0 CTS 6.5	Workload Dep.	SEQ 128KiB
		REQUIRED:	Data Pattern
		Tester's Choice:	RND
		OIO/Thread (QD)	16
		Thread Count (TC)	2
		Convergence	YES
		Rounds	4-8
		PC AR	100%
		AR AMOUNT	100%
		AR Segments	N/A
Enterprise 128KiB Throughput - ALL RW Mix & BS - Tabular Data			

Block Size (KiB)	Read / Write Mix %	
	0/100	100/0
128	144.5	409.3

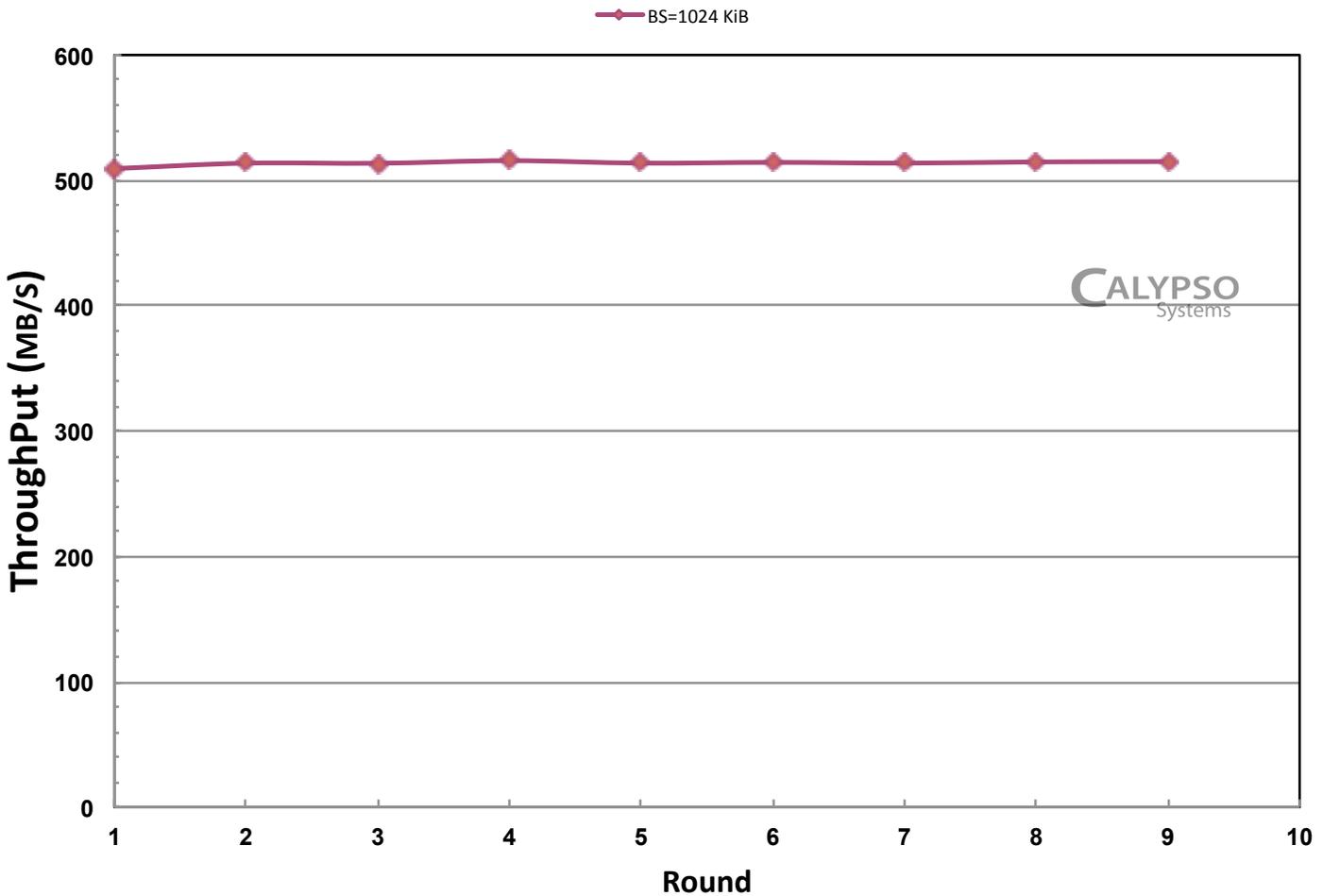
Test Run Date: 12/03/2011 04:32 PM		Report Run Date: 12/04/2011 10:04 AM	
Enterprise Throughput Test (REQUIRED) - Report Page			
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)			Rev. PTS-E 1.0
			Page 5 of 5
Device Under Test (DUT)	VENDOR: ABC CO.	SSD MODEL NO: SLC-A 100 GB	TEST SPONSOR CALYPSO Systems
Serial No.	1111-0000-FFFF	DUT Preparation	Test Loop Parameters
Firmware Rev	BFOA	Purge	Format Unit
Capacity	100 GB	REQUIRED:	
NAND Type	SLC	Pre-Conditioning	Data Pattern RND
Device I/F	6 Gb/s SAS	Workload Independent	2X SEQ/128KiB
Test Platform	RTP 2.0 CTS 6.5	Workload Dep.	SEQ 128KiB
		Tester's Choice:	
		OIO/Thread (QD)	16
		Thread Count (TC)	2
		Convergence	YES
		Rounds	4-8
		PC AR	100%
		AR AMOUNT	100%
		AR Segments	N/A
Enterprise 128KiB Throughput - ALL RW Mix & BS - 2D Plot			



Test Run Date: 12/04/2011 08:21 AM		Report Run Date: 12/04/2011 10:03 AM	
Enterprise Throughput Test (REQUIRED) - Report Page			
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)			Rev. PTS-E 1.0
			Page 1 of 5
Device Under Test (DUT)	VENDOR: ABC CO.	SSD MODEL NO: SLC-A 100 GB	TEST SPONSOR CALYPSO Systems
Serial No.	1111-0000-FFFF	DUT Preparation	Test Loop Parameters
Firmware Rev	BFOA	Purge	Format Unit
Capacity	100 GB	Pre-Conditioning	
NAND Type	SLC	Workload Independent	2X SEQ/128KiB
Device I/F	6 Gb/s SAS		
Test Platform	RTP 2.0 CTS 6.5	Workload Dep.	SEQ 1024KiB
		REQUIRED:	Steady State
		Data Pattern	RND
		Tester's Choice:	
		OIO/Thread (QD)	16
		Thread Count (TC)	2
		Convergence	YES
		Rounds	4-8
		PC AR	100%
		AR AMOUNT	100%
		AR Segments	N/A
Enterprise 1024KiB Throughput Test - SS Convergence - Write			



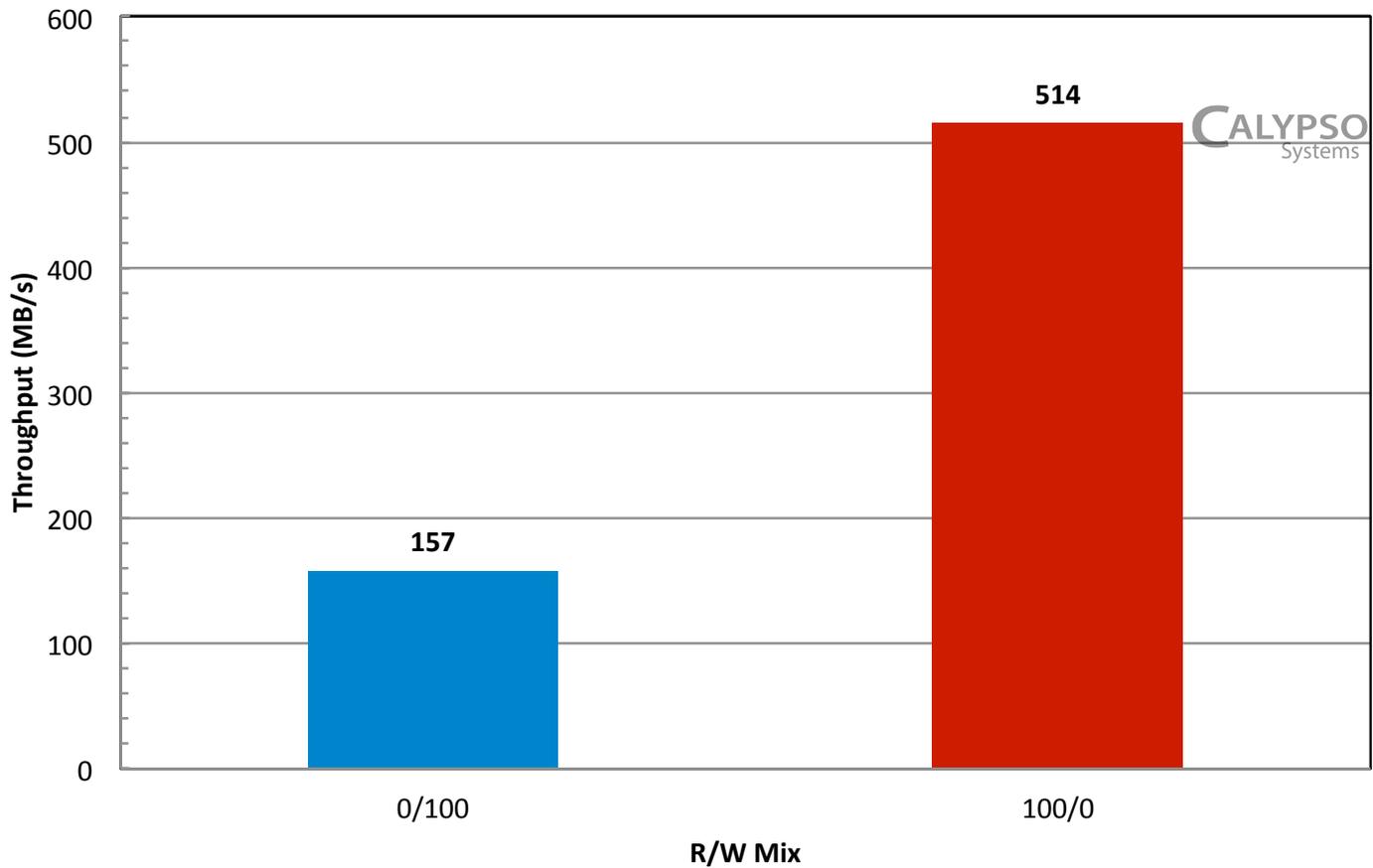
Test Run Date: 12/04/2011 08:21 AM		Report Run Date: 12/04/2011 10:03 AM	
Enterprise Throughput Test (REQUIRED) - Report Page			
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)			Rev. PTS-E 1.0
			Page 2 of 5
Device Under Test (DUT)	VENDOR: ABC CO.	SSD MODEL NO: SLC-A 100 GB	TEST SPONSOR CALYPSO Systems
Serial No.	1111-0000-FFFF	DUT Preparation	Test Loop Parameters
Firmware Rev	BFOA	Purge	Format Unit
Capacity	100 GB	Pre-Conditioning	
NAND Type	SLC	Workload Independent	2X SEQ/128KiB
Device I/F	6 Gb/s SAS		
Test Platform	RTP 2.0 CTS 6.5	Workload Dep.	SEQ 1024KiB
		REQUIRED:	Data Pattern
		Tester's Choice:	RND
		OIO/Thread (QD)	16
		Thread Count (TC)	2
		Convergence	YES
		Rounds	4-8
		PC AR	100%
		AR AMOUNT	100%
		AR Segments	N/A
Enterprise 1024KiB Throughput Test - SS Convergence - Read			



Test Run Date: 12/04/2011 08:21 AM		Report Run Date: 12/04/2011 10:03 AM	
Enterprise Throughput Test (REQUIRED) - Report Page			
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)			Rev. PTS-E 1.0
			Page 4 of 5
Device Under Test (DUT)	VENDOR: ABC CO.	SSD MODEL NO: SLC-A 100 GB	TEST SPONSOR 
Serial No.	1111-0000-FFFF	DUT Preparation	Test Loop Parameters
Firmware Rev	BFOA	Purge	Format Unit
Capacity	100 GB	Pre-Conditioning	
NAND Type	SLC	Workload Independent	2X SEQ/128KiB
Device I/F	6 Gb/s SAS		
Test Platform	RTP 2.0 CTS 6.5	Workload Dep.	SEQ 1024KiB
		REQUIRED:	Data Pattern
		Tester's Choice:	RND
		OIO/Thread (QD)	16
		Thread Count (TC)	2
		Convergence	YES
		Rounds	4-8
		PC AR	100%
		AR AMOUNT	100%
		AR Segments	N/A
Enterprise 1024KiB Throughput - ALL RW Mix & BS - Tabular Data			

Block Size (KiB)	Read / Write Mix %	
	0/100	100/0
1024	157.5	514.3

Test Run Date: 12/04/2011 08:21 AM		Report Run Date: 12/04/2011 10:03 AM	
Enterprise Throughput Test (REQUIRED) - Report Page			
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)			Rev. PTS-E 1.0
			Page 5 of 5
Device Under Test (DUT)	VENDOR: ABC CO.	SSD MODEL NO: SLC-A 100 GB	TEST SPONSOR CALYPSO Systems
Serial No.	1111-0000-FFFF	DUT Preparation	Test Loop Parameters
Firmware Rev	BFOA	Purge	Format Unit
Capacity	100 GB	REQUIRED:	
NAND Type	SLC	Pre-Conditioning	Data Pattern RND
Device I/F	6 Gb/s SAS	Workload Independent	2X SEQ/128KiB
Test Platform	RTP 2.0 CTS 6.5	Workload Dep.	SEQ 1024KiB
		Tester's Choice:	OIO/Thread (QD) 16
			Thread Count (TC) 2
			Steady State
		Convergence	YES
		Rounds	4-8
		PC AR	100%
		AR AMOUNT	100%
		AR Segments	N/A
Enterprise 1024KiB Throughput - ALL RW Mix & BS - 2D Plot			



SLC-A Test Report

Summary Report Page - LATENCY

SNIA Solid State Storage Performance Test Specification (PTS)						Rev.	PTS 1.0
						Page	25 of 31
Device Under Test (DUT)	SLC-A	SNIA SSS PTS Summary Report		Calypso Systems, Inc.		CALYPSO Systems	
DEVICE INFORMATION		TEST HARDWARE PLATFORM		TEST SOFTWARE		REPORT DATE	
SERIAL NO.	1111-0000-FFFF	SYSTEM	Calypso RTP 2.0	SYS OS	CENT OS 5.6	Report	06DEC11
FIRMWARE REV.	BFOA	Motherboard/cpu	Intel 5520HC / W5580	SW TOOL	Calypso CTS 6.5	Test Run	01NOV - 04DEC11
USER CAPACITY	SLC 100 GB	RAM	12GB ECC DDR3	SW Rev	1.19.10	Test Sponsor	Calypso
DEVICE INTERFACE	6 Gb/s SATAII	Device Interface	LSA 9212-e 6Gb/s HBA	Release	Nov. 2011	Auditor	N/A

Test Description

Purpose	To measure AVE & MAX Response times at selected BS & RW Mixes measured in mSec
Test Outline	PURGE, then apply preconditioning until Steady State is achieved according to the SNIA PTS
Preconditioning	PURGE followed by SNIA PTS prescribed WIPC & WDPC

Test Set Up

PTS-C	TEST	Purge	DP	OIO	WIPC		WDPC		STEADY STATE	
10.0	LATENCY - REQUIRED	Format Unit	RND	TC 1 QD 1	PC AR	TEST AR	PC AR	TEST AR	WORKLOAD	ROUNDS
					100%	100%	100%	100%	LAT LOOP	3 - 7

Select Performance Data

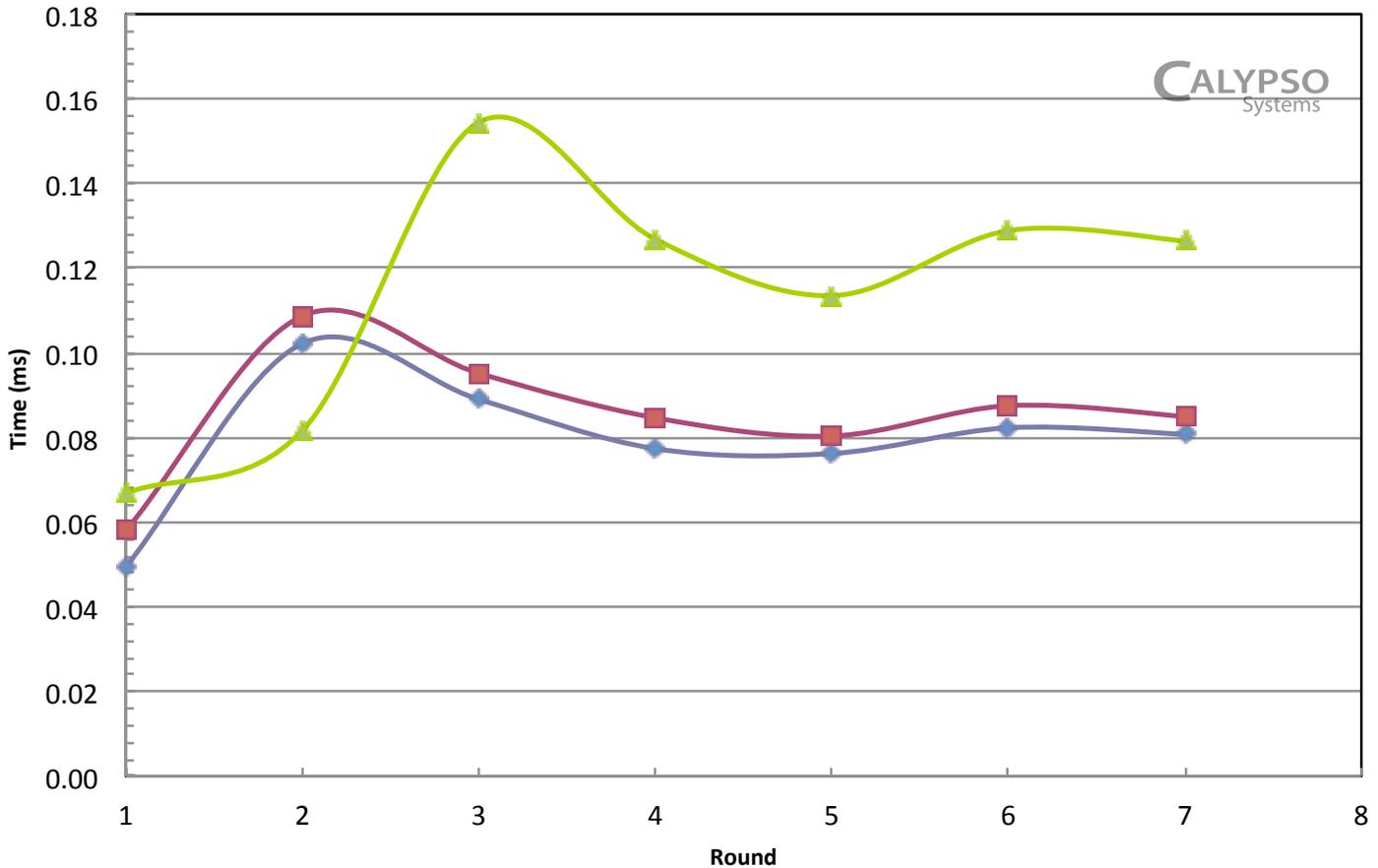
RND 4KiB R AVE	RND 4KiB W AVE	RND 4KiB R MAX	RND 4KiB W MAX
0.160 mSec	0.090 mSec	6.26 mSec	32.63 mSec

Test Sponsor – Special Notes

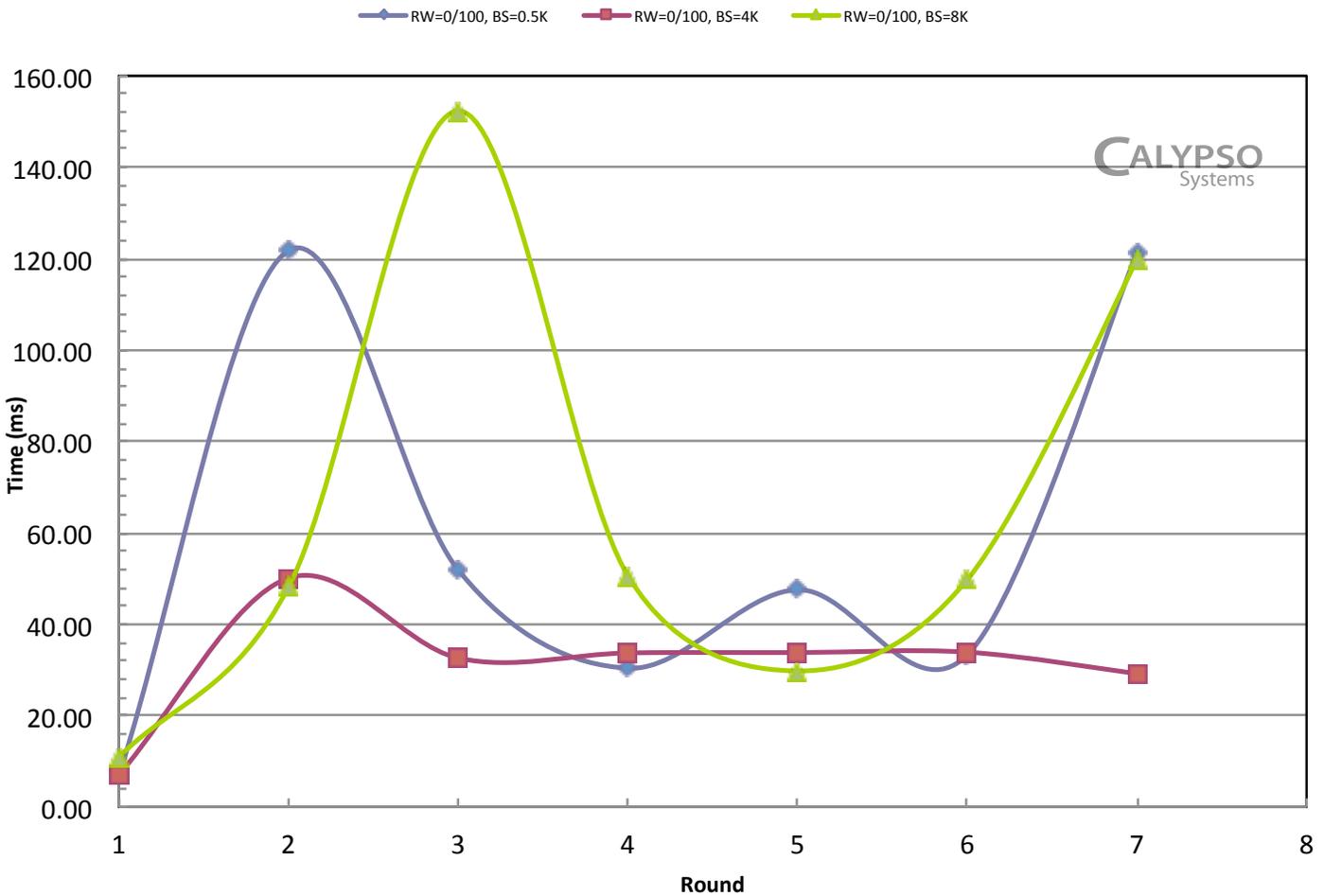
ITEM	NOTATION	COMMENTS

Test Run Date:		11/10/2011 05:07 AM		Report Run Date:		11/14/2011 08:47 AM		
Enterprise Latency (REQUIRED) - Report Page								
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)						Rev.	PTS-E 1.0	
						Page	1 of 6	
Device Under Test (DUT)		VENDOR: ABC CO.	SSD MODEL NO: SLC-A 100 GB		TEST SPONSOR	CALYPSO Systems		
Serial No.	1111-0000-FFFF	DUT Preparation		Test Loop Parameters				Steady State
Firmware Rev	BFOA	Purge	Format Unit		REQUIRED:		Convergence	YES
Capacity	100 GB	Pre-Conditioning		Data Pattern		RND	Rounds	3-7
NAND Type	SLC	Workload Independent	2X SEQ/128KiB		Tester's Choice:		PC AR	100%
Device I/F	6 Gb/s SAS		Workload Dep.	Full LAT Loop		OIO/Thread (QD)		AR AMOUNT
Test Platform	RTP 2.0 CTS 6.5			Thread Count (TC)			AR Segments	N/A
Enterprise Steady State Convergence Plot - AVE Latency - 100% Writes								

◆ RW=0/100, BS=0.5K
■ RW=0/100, BS=4K
▲ RW=0/100, BS=8K

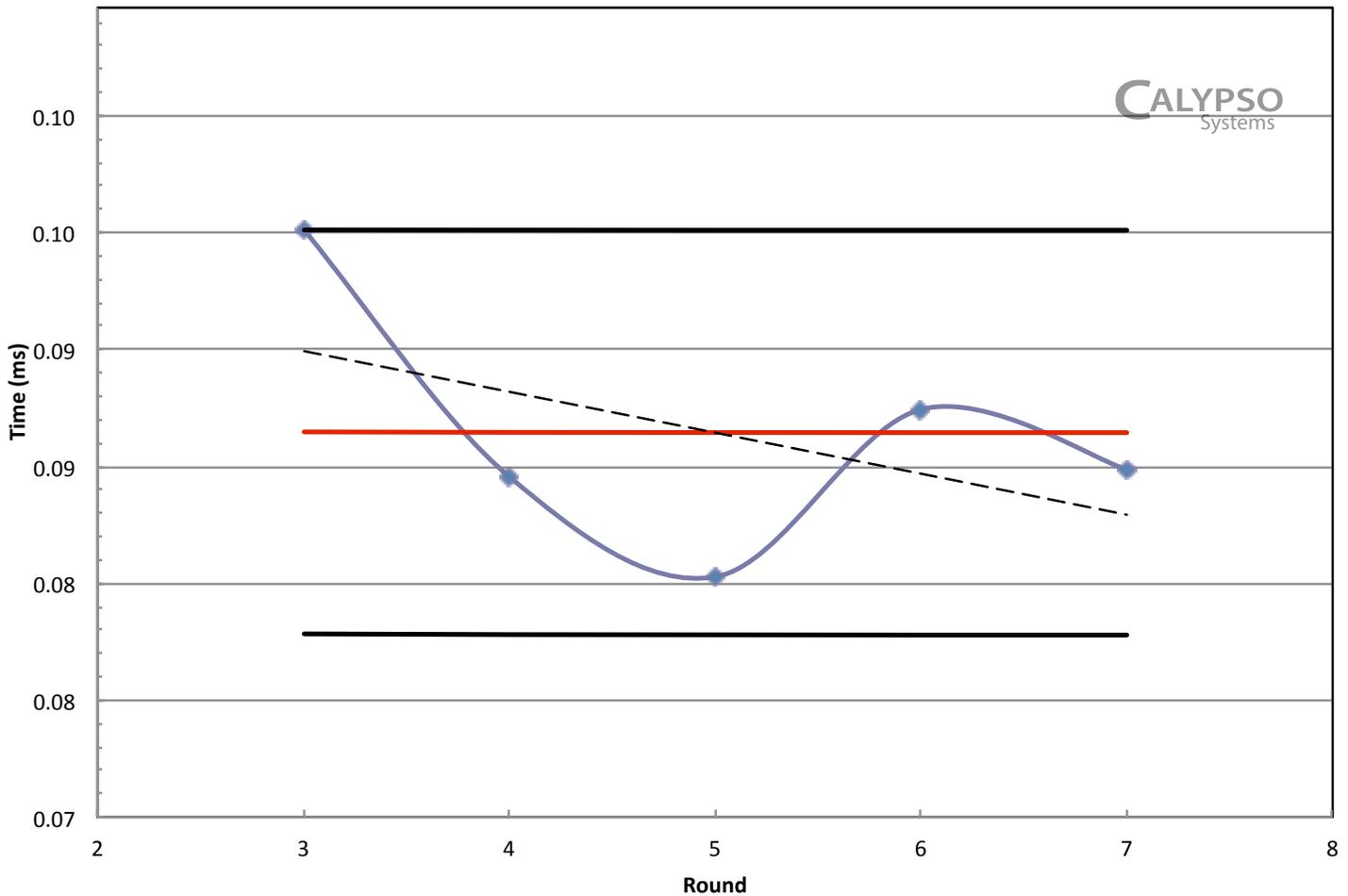


Test Run Date: 11/10/2011 05:07 AM		Report Run Date: 11/14/2011 08:47 AM	
Enterprise Latency (REQUIRED) - Report Page			
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)			Rev. PTS-E 1.0
			Page 2 of 6
Device Under Test (DUT)	VENDOR: ABC CO.	SSD MODEL NO: SLC-A 100 GB	TEST SPONSOR CALYPSO Systems
Serial No.	1111-0000-FFFF	DUT Preparation	Test Loop Parameters
Firmware Rev	BFOA	Purge	Format Unit
Capacity	100 GB	Pre-Conditioning	
NAND Type	SLC	Workload Independent	2X SEQ/128KiB
Device I/F	6 Gb/s SAS		
Test Platform	RTP 2.0 CTS 6.5	Workload Dep.	Full LAT Loop
		REQUIRED:	Data Pattern
		Tester's Choice:	RND
		OIO/Thread (QD)	1
		Thread Count (TC)	1
		Convergence	YES
		Rounds	3-7
		PC AR	100%
		AR AMOUNT	100%
		AR Segments	N/A
Enterprise Steady State Convergence Plot – MAX Latency - 100% Writes			



Test Run Date: 11/10/2011 05:07 AM		Report Run Date: 11/14/2011 08:47 AM	
Enterprise Latency (REQUIRED) - Report Page			
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)			Rev. PTS-E 1.0
			Page 3 of 6
Device Under Test (DUT)	VENDOR: ABC CO.	SSD MODEL NO: SLC-A 100 GB	TEST SPONSOR CALYPSO Systems
Serial No.	1111-0000-FFFF	DUT Preparation	Test Loop Parameters
Firmware Rev	BFOA	Purge	Format Unit
Capacity	100 GB	Pre-Conditioning	
NAND Type	SLC	Workload Independent	2X SEQ/128KiB
Device I/F	6 Gb/s SAS		
Test Platform	RTP 2.0 CTS 6.5	Workload Dep.	Full LAT Loop
		REQUIRED:	Data Pattern
		Tester's Choice:	RND
		OIO/Thread (QD)	1
		Thread Count (TC)	1
		Convergence	YES
		Rounds	3-7
		PC AR	100%
		AR AMOUNT	100%
		AR Segments	N/A
Enterprise Steady State Measurement Window – RND/4KiB			

—●— Ave Latency
— Average
— 110%*Average
- - - 90%*Average



Steady State Determination Data

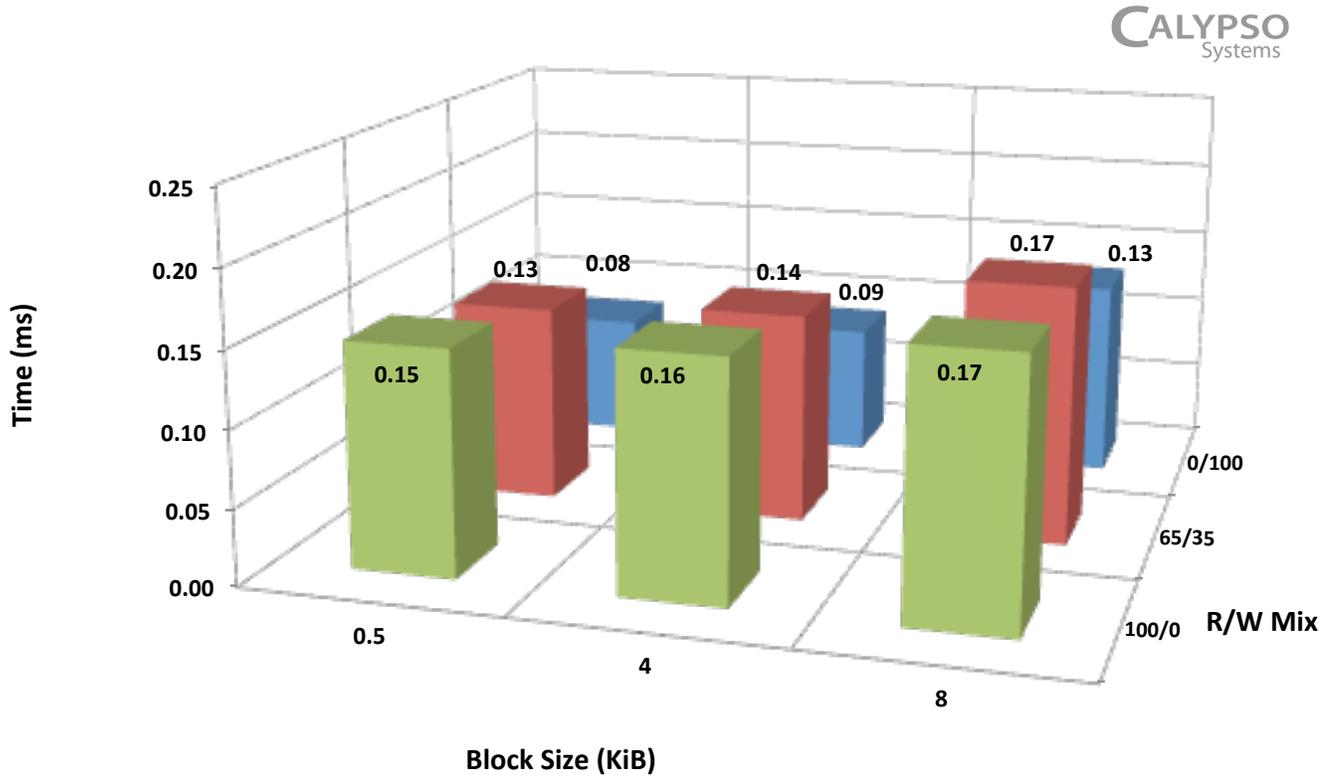
Average Latency (ms):		0.087	
Allowed Maximum Data Excursion:	0.017	Measured Maximum Data Excursion:	0.015
Allowed Maximum Slope Excursion:	0.009	Measured Maximum Slope Excursion:	0.007
Least Squares Linear Fit Formula:		-0.002 * R + 0.095	

Test Run Date:		11/10/2011 05:07 AM		Report Run Date:		11/14/2011 08:47 AM		
Enterprise Latency (REQUIRED) - Report Page								
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)						Rev.	PTS-E 1.0	
						Page	4 of 6	
Device Under Test (DUT)		VENDOR: ABC CO.	SSD MODEL NO: SLC-A 100 GB		TEST SPONSOR	CALYPSO Systems		
Serial No.	1111-0000-FFFF	DUT Preparation		Test Loop Parameters		Steady State		
Firmware Rev	BFOA	Purge	Format Unit		REQUIRED:	Convergence	YES	
Capacity	100 GB	Pre-Conditioning		Data Pattern	RND	Rounds	3-7	
NAND Type	SLC	Workload Independent	2X SEQ/128KiB		Tester's Choice:	PC AR	100%	
Device I/F	6 Gb/s SAS		Full LAT Loop			OIO/Thread (QD)	1	AR AMOUNT
Test Platform	RTP 2.0 CTS 6.5	Workload Dep.			Thread Count (TC)	1	AR Segments	N/A
Enterprise AVE and MAX Response Time - ALL RW Mix & BS - Tabular Data								

Average Response Time (ms)			
	Read / Write Mix %		
Block Size (KiB)	0/100	65/35	100/0
0.5	0.08	0.13	0.15
4	0.09	0.14	0.16
8	0.13	0.17	0.17

Maximum Response Time (ms)			
	Read / Write Mix %		
Block Size (KiB)	0/100	65/35	100/0
0.5	56.87	39.46	5.80
4	32.63	46.78	6.26
8	80.43	39.38	12.99

Test Run Date:		11/10/2011 05:07 AM		Report Run Date:		11/14/2011 08:47 AM		
Enterprise Latency (REQUIRED) - Report Page								
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)						Rev.	PTS-E 1.0	
						Page	5 of 6	
Device Under Test (DUT)		VENDOR:	SSD MODEL NO:		TEST SPONSOR	CALYPSO Systems		
		ABC CO.	SLC-A 100 GB					
Serial No.	1111-0000-FFFF	DUT Preparation		Test Loop Parameters		Steady State		
Firmware Rev	BFOA	Purge	Format Unit		REQUIRED:		Convergence	YES
Capacity	100 GB	Pre-Conditioning		Data Pattern		RND	Rounds	3-7
NAND Type	SLC	Workload Independent	2X SEQ/128KiB		Tester's Choice:		PC AR	100%
Device I/F	6 Gb/s SAS		Workload Dep.	Full LAT Loop		OIO/Thread (QD)		AR AMOUNT
Test Platform	RTP 2.0 CTS 6.5			Thread Count (TC)		1	AR Segments	N/A
Enterprise AVE Latency vs BS and R/W Mix - 3D Plot								



Test Run Date:		11/10/2011 05:07 AM		Report Run Date:		11/14/2011 08:47 AM		
Enterprise Latency (REQUIRED) - Report Page								
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)						Rev.	PTS-E 1.0	
						Page	6 of 6	
Device Under Test (DUT)		VENDOR: ABC CO.	SSD MODEL NO: SLC-A 100 GB		TEST SPONSOR	CALYPSO Systems		
Serial No.	1111-0000-FFFF	DUT Preparation		Test Loop Parameters				Steady State
Firmware Rev	BFOA	Purge	Format Unit		REQUIRED:		Convergence	YES
Capacity	100 GB	Pre-Conditioning		Data Pattern		RND	Rounds	3-7
NAND Type	SLC	Workload Independent	2X SEQ/128KiB		Tester's Choice:		PC AR	100%
Device I/F	6 Gb/s SATA		Workload Dep.	Full LAT Loop		OIO/Thread (QD)		AR AMOUNT
Test Platform	RTP 2.0 CTS 6.5			Thread Count (TC)		1	AR Segments	N/A
Enterprise MAX Latency vs BS and R/W Mix - 3D Plot								

